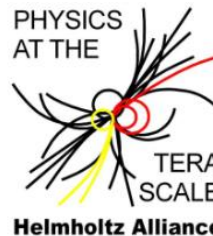




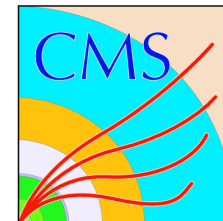
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The CMS Tracker Upgrade

Georg Steinbrück (Hamburg University)
on behalf of the CMS Tracker Collaboration

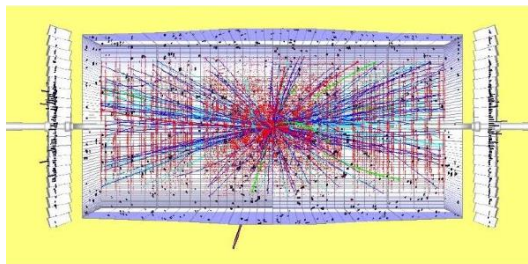
23rd RD50 workshop
CERN – November 13-15, 2013


Content

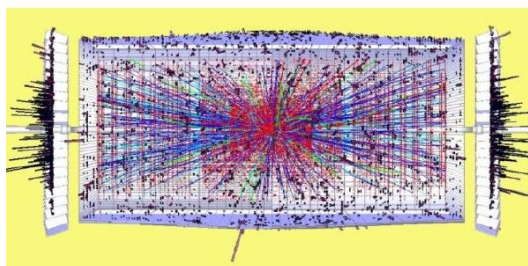
- Introduction to the Upgrade of the CMS Tracking Detectors for Phase II
 - Triggering at L1
 - Detector Modules for the Outer Tracker
 - The HPK Measurement and Irradiation campaign
 - Leakage Current
 - Depletion Voltage
 - Signal
 - Conclusions
-
- Note: CMS has seen non-Gaussian noise in irradiated p-in-n strip sensors. Not covered in this talk → See talk by Andreas Nürnberg

Upgrade of the CMS Tracker: Timeline

2013	Long Shutdown 1	<ul style="list-style-type: none"> • Consolidation: Improvement of tracker thermal and humidity insulation • New beam pipe • Installation of pixel test slice } preparation for phase-1
2014		
2015	<i>Data taking</i>	operation at lower temperature
2016		
Technical stop		Installation of new CMS phase-1 pixel detector
2017	<i>"Phase-1"</i>	
2018	LS2	
2019	<i>Data taking "Phase-1" $\approx 500 \text{ fb}^{-1}$</i>	Exchange of innermost pixel layer after $\sim 250 \text{ fb}^{-1}$
2020		
2021		
2022	LS3	Installation of a new CMS tracker <ul style="list-style-type: none"> • Phase-2 pixel detector • Phase-2 outer tracker • Track trigger
2023		
2024	<i>Data taking "Phase-2" $\approx 3000 \text{ fb}^{-1}$</i>	
↓		



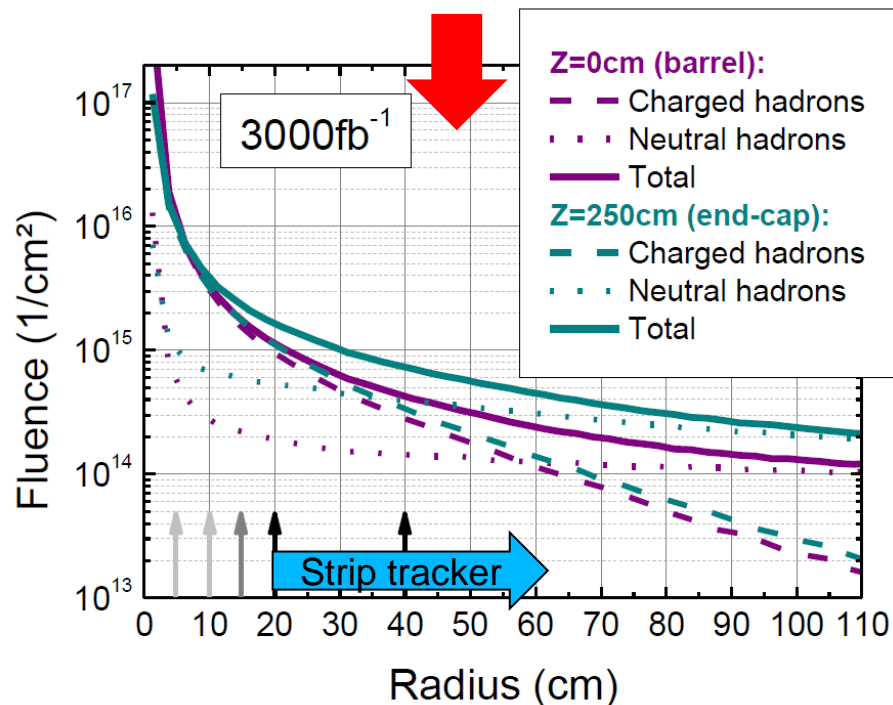
x5 in  instantaneous luminosity:



Up to 200 collisions per bunch X!

- Keep occupancy at %-level and resolve vertices → shorter strips
- Improve performance at high pT → smaller pitch
- Reduce rates → Triggering at L1
- Improve low pT tracking → material budget!

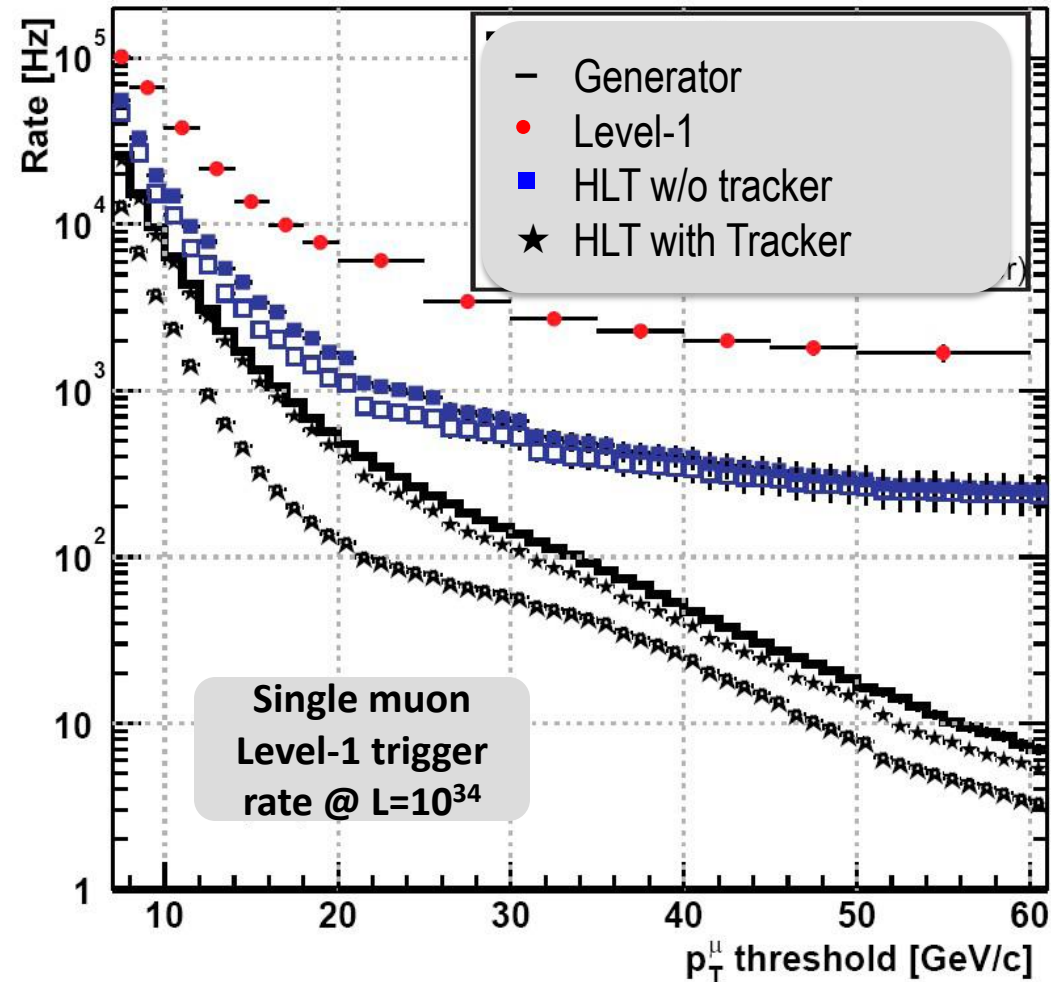
x6 in integrated luminosity:



- **Radiation hard silicon** and suitable sensor designs needed
- Cooling to -20°C

Motivation for L1 Track Finding

- μ , e , jet rates would become unacceptably large at high luminosity
- Higher trigger thresholds would degrade physics performance and have a limit due to resolution: See single μ
- Use tracking information already at L1
- Goal: Reconstruct tracks above 2 GeV
- Identify their origin within 1mm along the beam axis



The CMS Tracker for the HL-LHC

Baseline tracker layout:

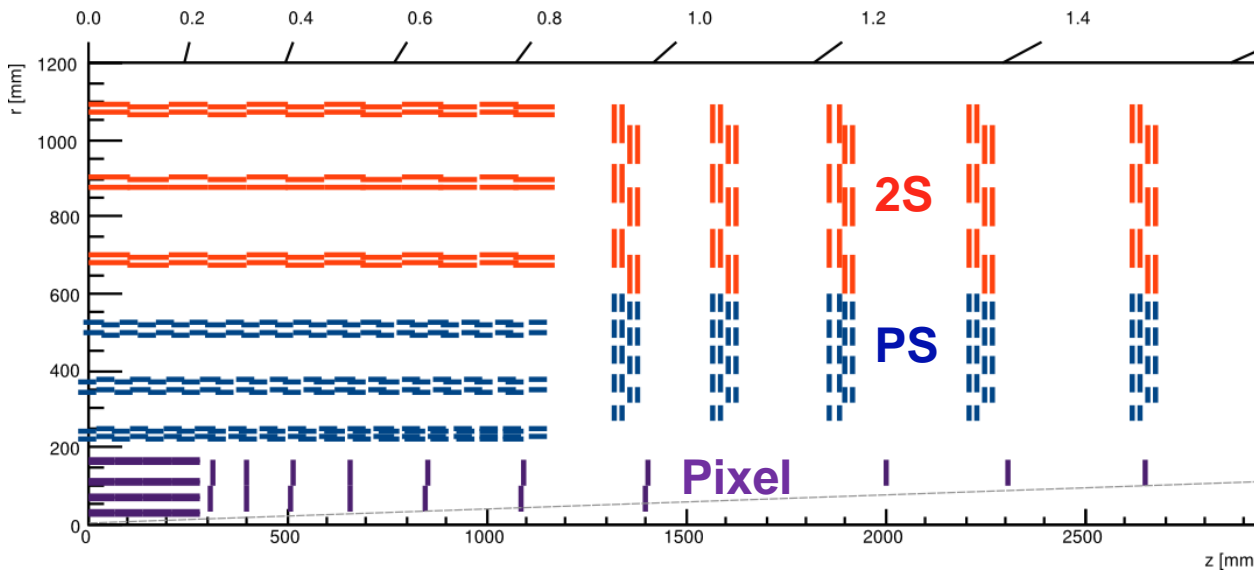
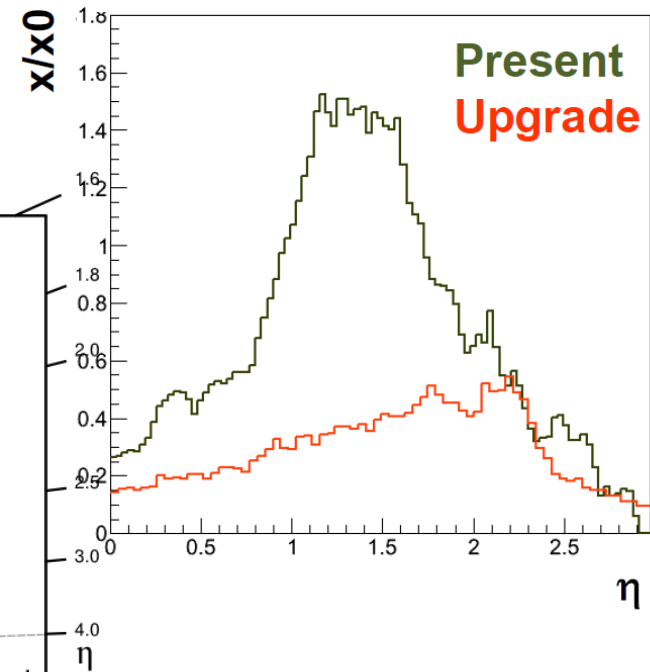
Barrel-Endcap design with 6 barrel layers and 5 endcap disks “BE5”

Layout driven by requirement to use tracks in L1 trigger (also by financial constraints)

→ Two kinds of stacked modules

- Strip-Strip (2S) modules for $r > 60$ cm
 - Spacing 1.8 and 4 mm
- Pixel-Strip (PS) modules for $r < 60$ cm
 - Spacing 1.6, 2.6 and 4 mm

Material budget estimate



New versus Old: Numbers

Current CMS Tracker

- Total # of modules 15,148
- Total active surface 210 m²
- Total # of strips 9.3 M
- Power in the tracking volume
~ 30 kW

Upgrade

- # of modules 15,508
 - 7084 PS modules
 - 8424 2S modules
- Total active surface 218 m²
 - 155 m² strips (2S)
 - 31 m² strips (PS)
 - 31 m² macro-pixels (PS)
- Total # of strips 47.8 M
- Total # of pixels 218 M
- Power in the tracking volume
~70 kW

New versus Old: Performance

Calculated performance with a “phase-1” pixel detector

Rapidity regions

C 0 – 0.8

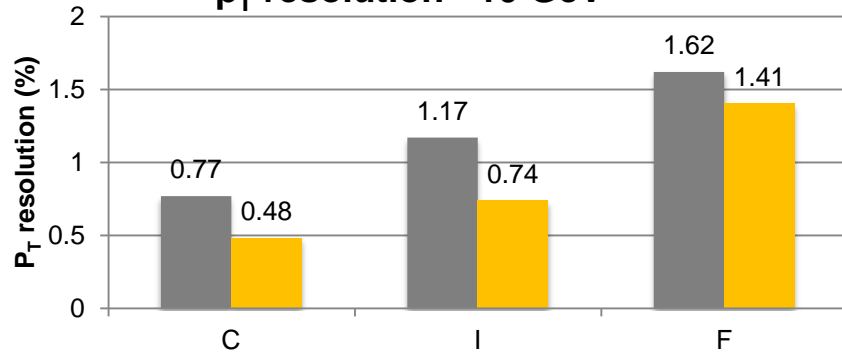
I 0.8 – 1.6

F 1.6 – 2.4

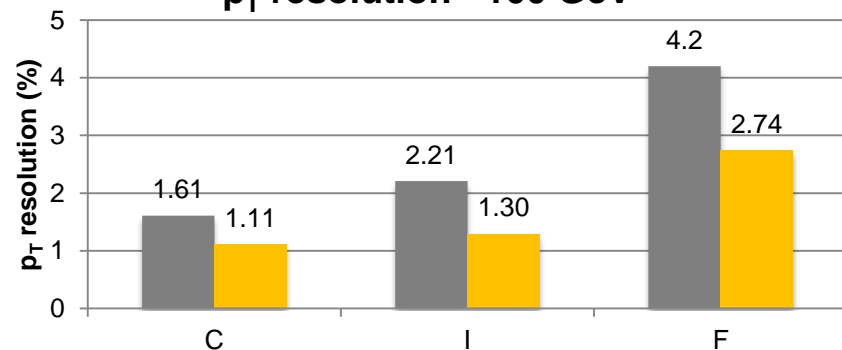
■ CMS

■ Upgrade

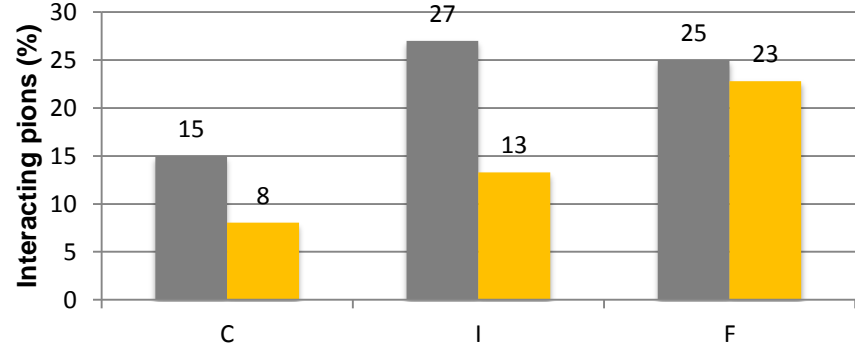
p_T resolution - 10 GeV



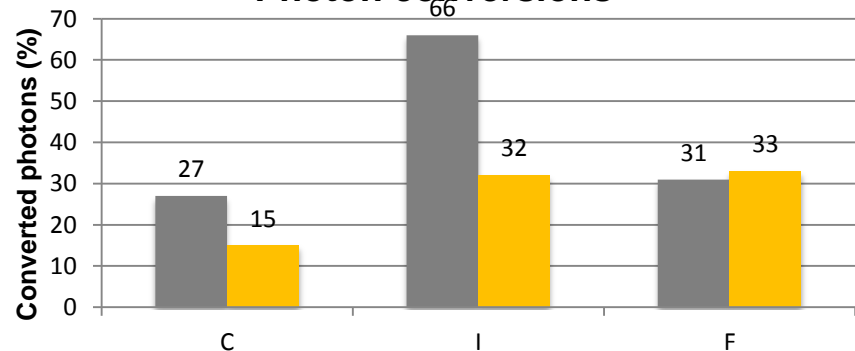
p_T resolution - 100 GeV



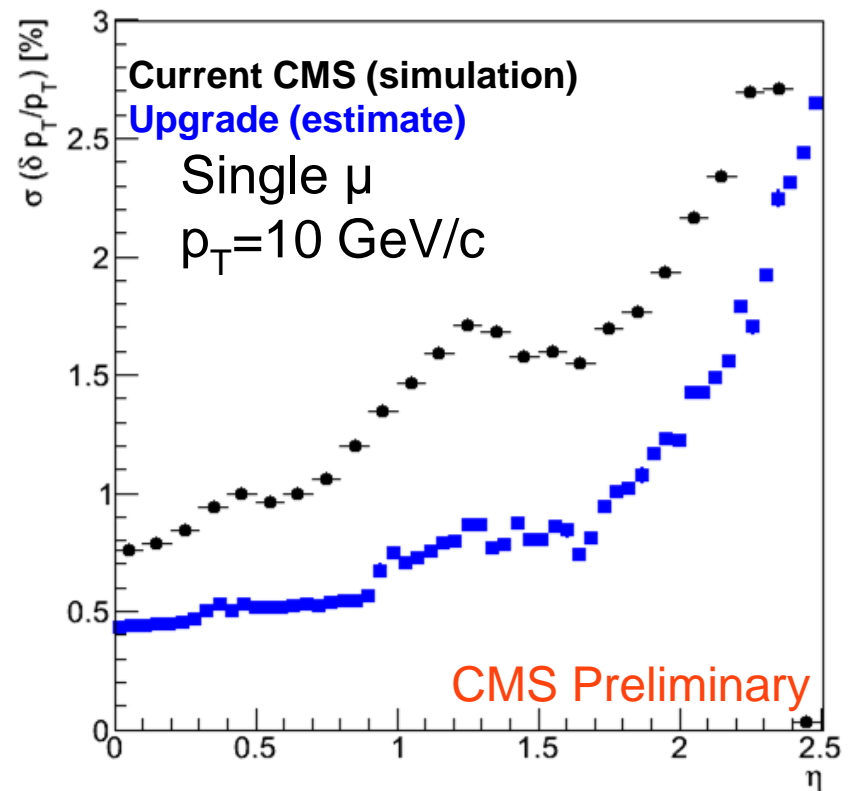
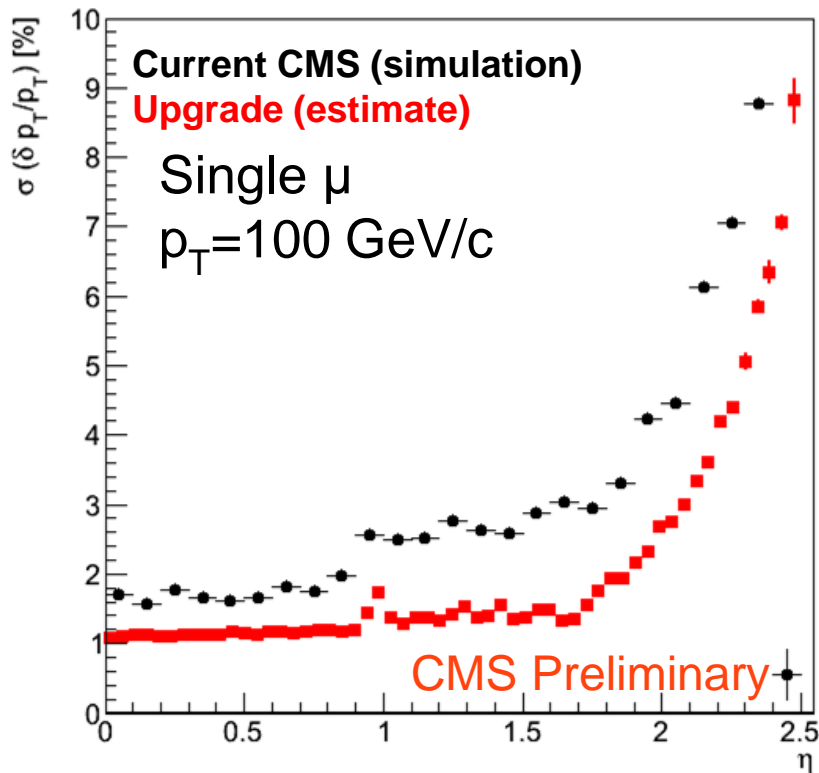
Pion interactions



Photon conversions



PT Resolution: Offline

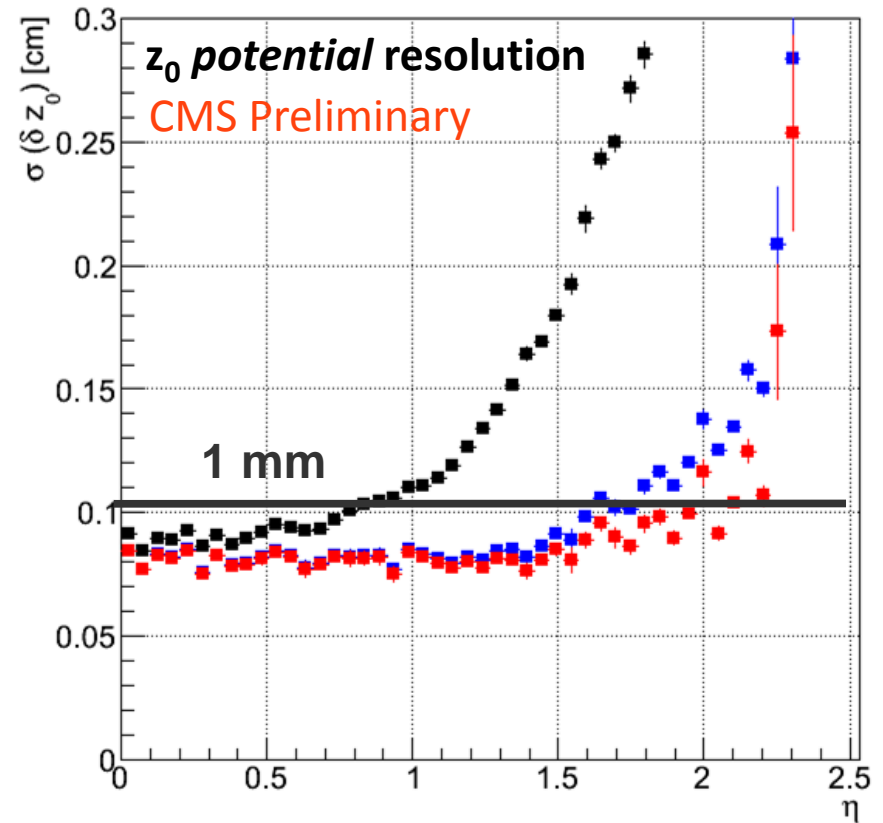
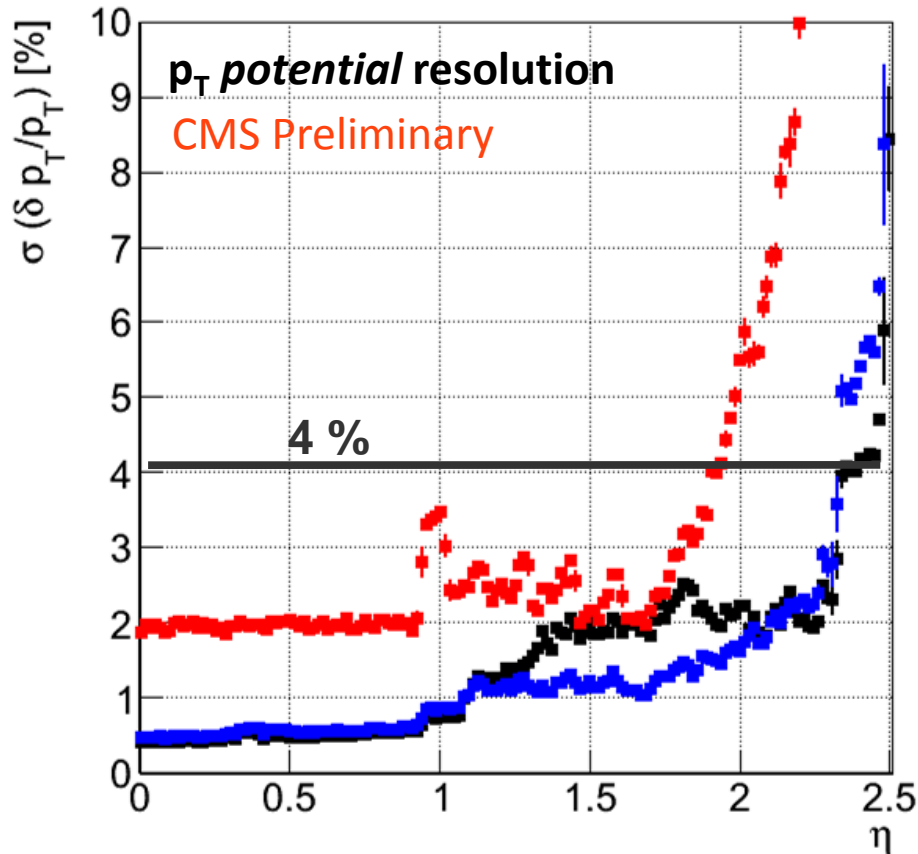


Significant improvement over all p_T and eta range.

Tracking Resolution @L1

Potential p_T resolution using all stub info

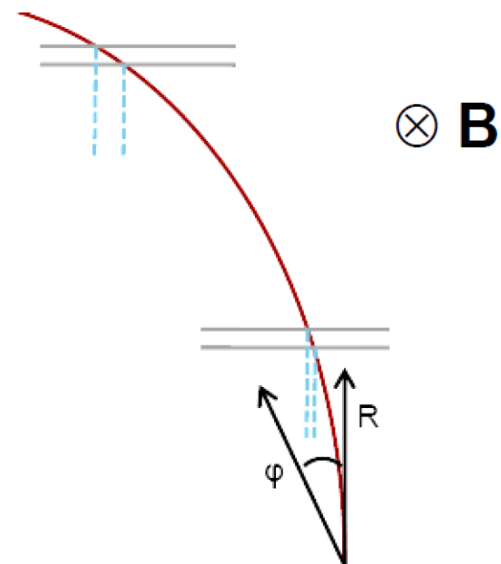
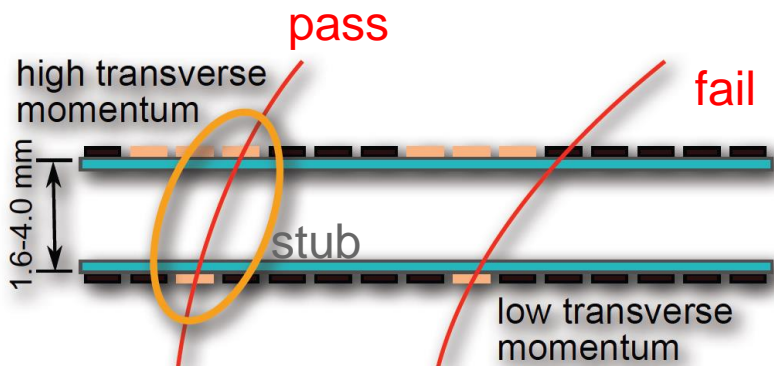
Single μ $p_T=2$ GeV/c
 Single μ $p_T=10$ GeV/c
 Single μ $p_T=100$ GeV/c



Very good resolution, especially at low p_T .

Track Finding @L1

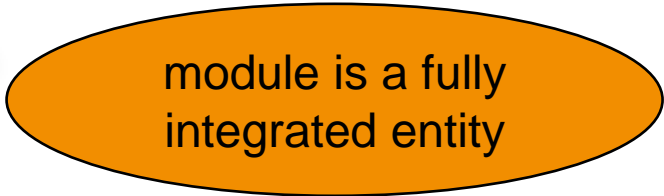
- > modules provide at the same time information
 - to L1 Trigger (at 40MHz)
 - as “read out data” after L1 decision (at 100kHz)
 → the whole tracker sends out sparsified data at each bunch crossing
- > p_T modules – modules with p_T discrimination
 - exploit bending in strong magnetic field
 - two closely spaced sensors read out by a single readout chip
 - correlate signals, look at cluster size
 → stubs sent out if within p_T cut



- > sensor spacing and window optimized for best performance
 - same geometrical cut corresponds to different p_T

Modules: General Concept

- binary readout – CBC
- low power giga-bit transceiver (LP-GBT) as data link
 - currently under development
 - integrated at module level
- powering via DC-DC conversion
 - already used in phase-1 pixel upgrade
 - input current at higher voltage ($\sim 10V$) reduces conductor cross-section, material budget
 - integrated at module level
- two different module types
 - different sensor spacings are treated as ‚variants‘ of one module type with only minimal changes
 - requires optimization of only two designs
- evaporative CO₂ is the baseline cooling system
 - experience within CMS is being gained with the phase-1 pixel upgrade



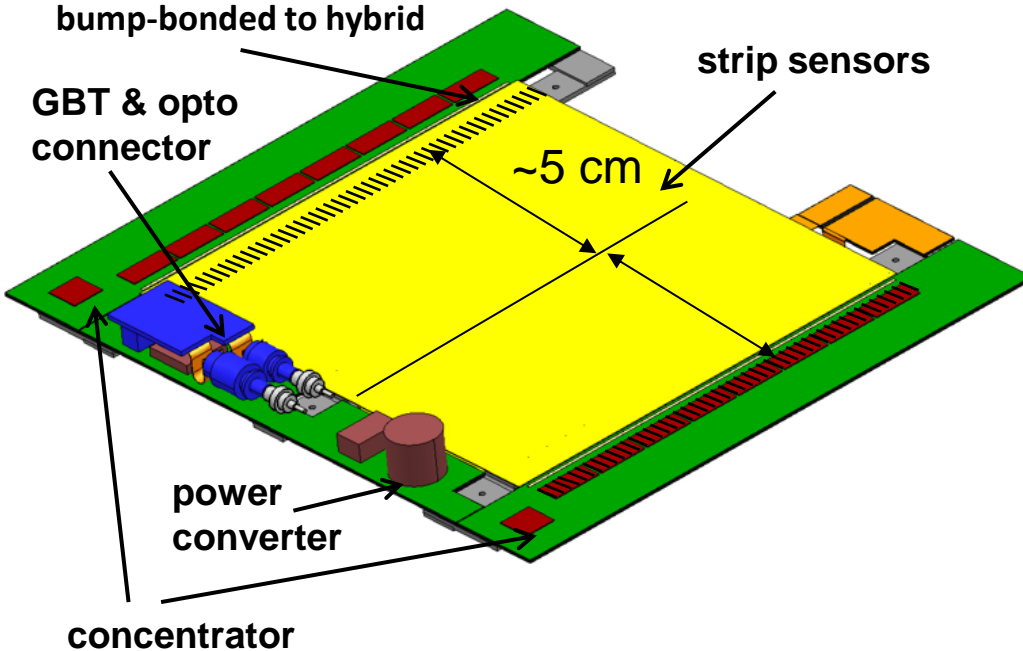
module is a fully integrated entity

Modules for the CMS Tracker Upgrade

2S p_T module

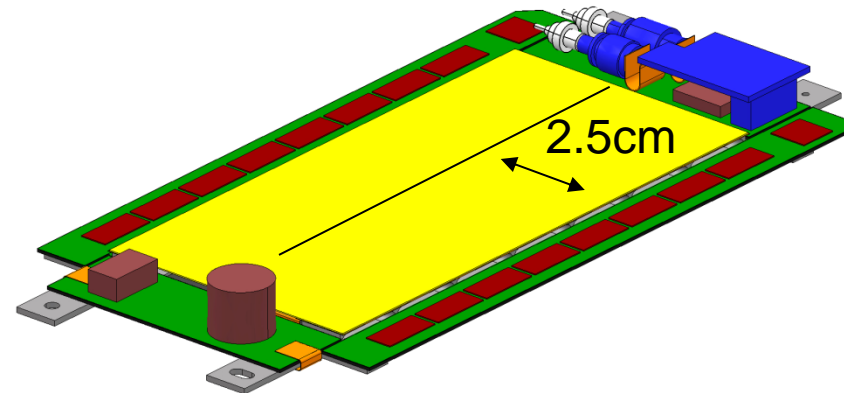
- for $r > 60\text{cm}$
- 2 strip sensors on top of each other
- sensors wire-bonded to hybrid from top & bottom
- strip dimensions: $5\text{cm} \times 90\mu\text{m}$
- $10\text{ cm} \times 10\text{ cm}$

(2x127) channel CBC chips
bump-bonded to hybrid

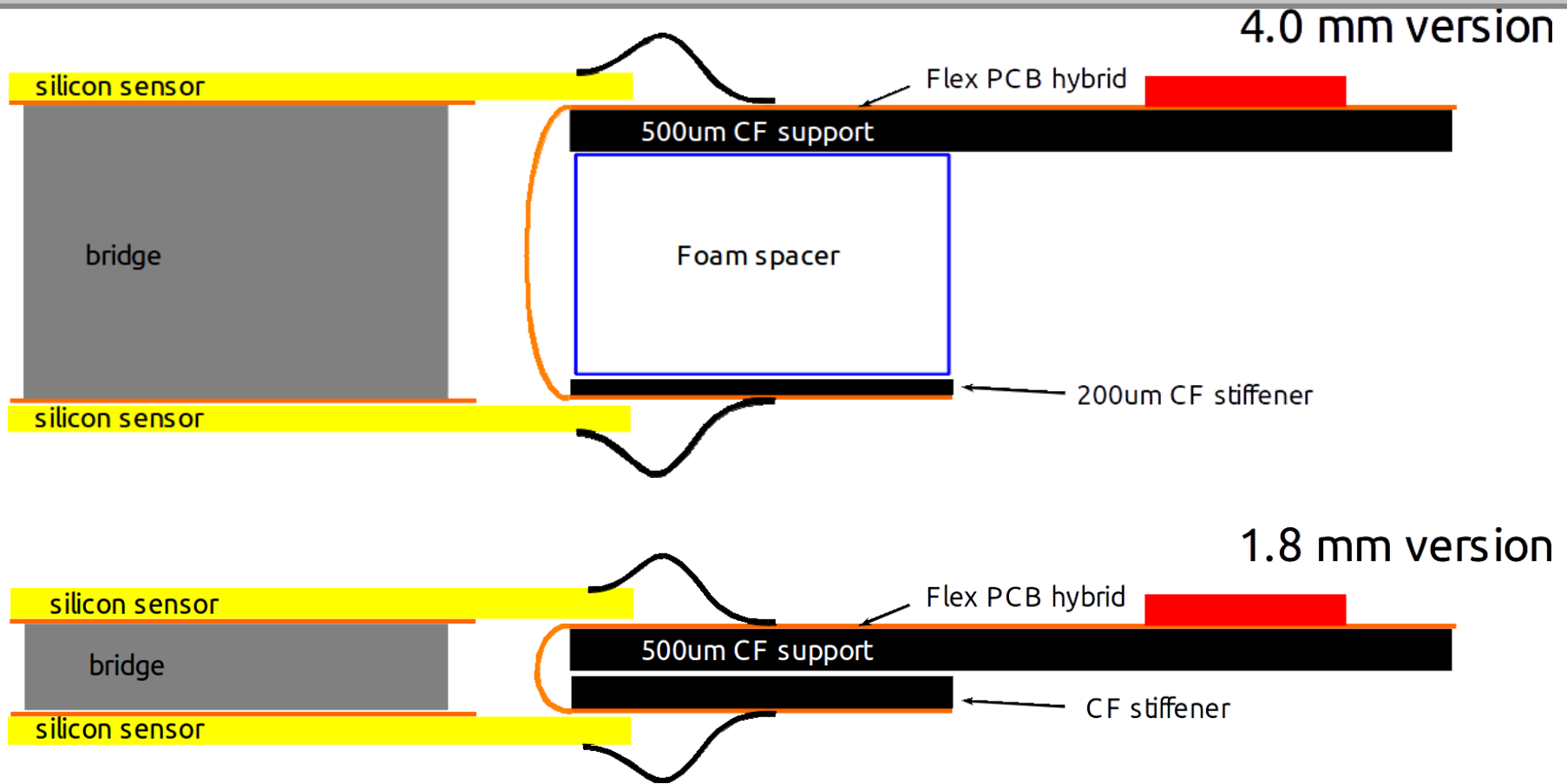


PS p_T module

- for $r > 20\text{cm}$
- 1 strip sensor and 1 pixel sensor on top of each other
- strip dimensions: $2.5\text{cm} \times 100\mu\text{m}$
- (macro)-pixel dimensions: $1.5\text{mm} \times 100\mu\text{m}$
- provides z information
- $5\text{ cm} \times 10\text{ cm}$



Connectivity/ hybrids



- Different sensor spacings obtained by variations of the same design.
- Alternative, rigid design also under consideration.

The CMS Binary Chip

IBM 130nm CMOS process

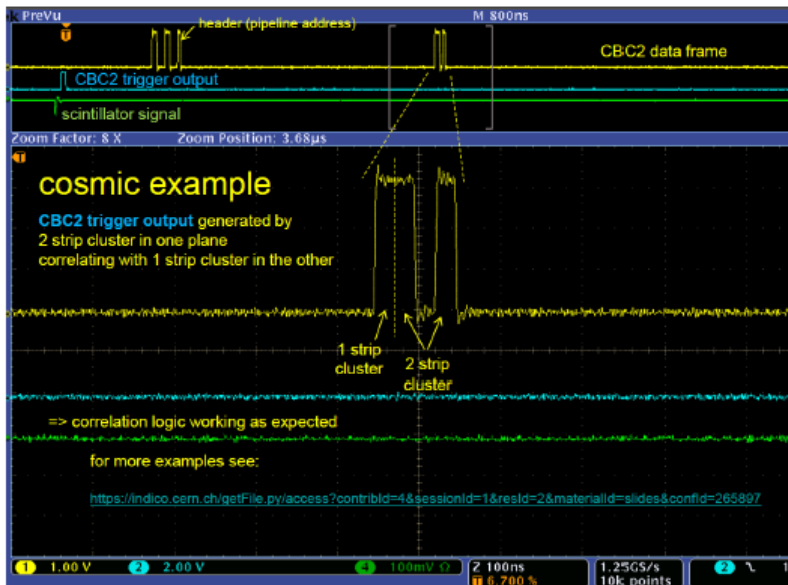
binary, unparsified architecture

- retains chip and system simplicity

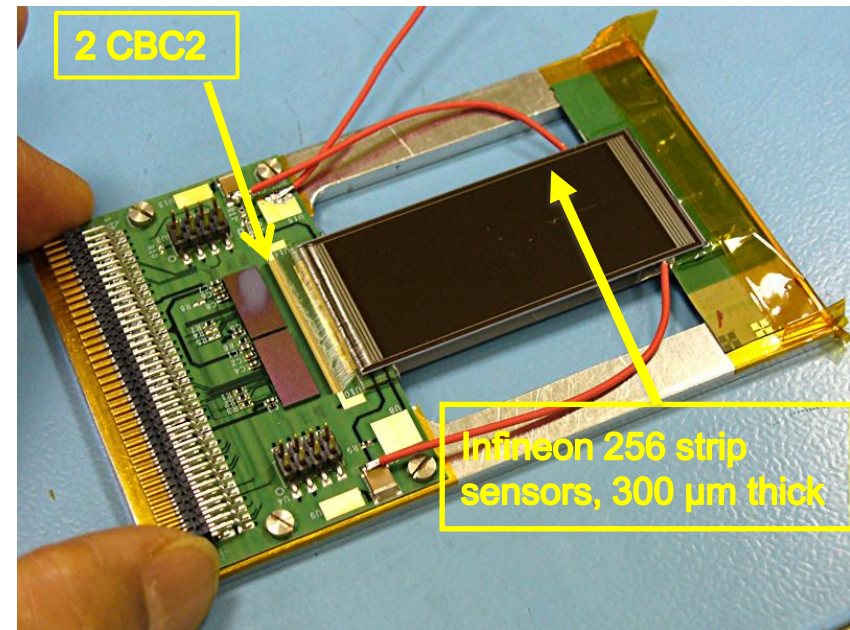
- but no pulse height data

receives data from both sensors

stub finding works



2 chip demonstrator module



- > testbeam in preparation
- > will use these CBC2 modules
- > show trigger capability in beam

Campaign to identify a suitable silicon sensor material and design choices for the outer tracker of CMS.

Important parameters:

- Bulk material: MCz vs. float zone: [O]
- Active sensor thickness
- Polarity: n versus p bulk
- Design parameters for strip detectors

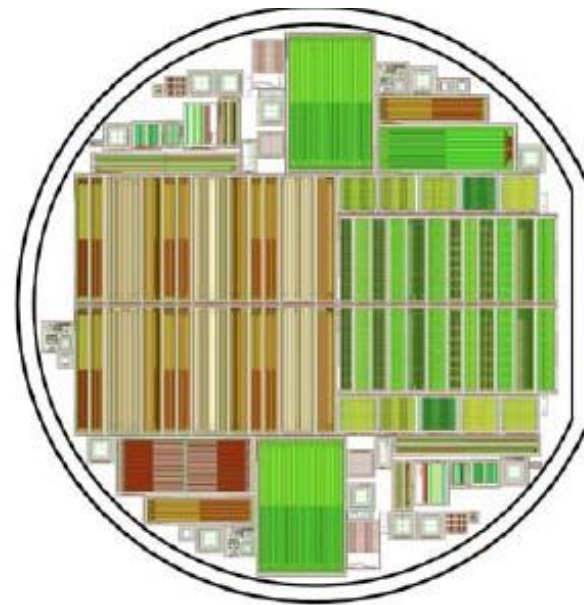
Chose single supplier (HPK) in order to compare sensors from same (or at least similar) processes.

Test radiation hardness:

- Irradiation with mix of protons and neutrons
- Fluences and neutron/proton ratio depend on radial distance from interaction point
- Study dependence on proton energy: 23 MeV, 800 MeV, 23 GeV

Structures include:

- Pad sensors (diodes) for material studies
- Mini-strip sensors for charge collection
- MSSD sensors to study geometry effects



> 100 wafers ordered

Prototype sensors produced:

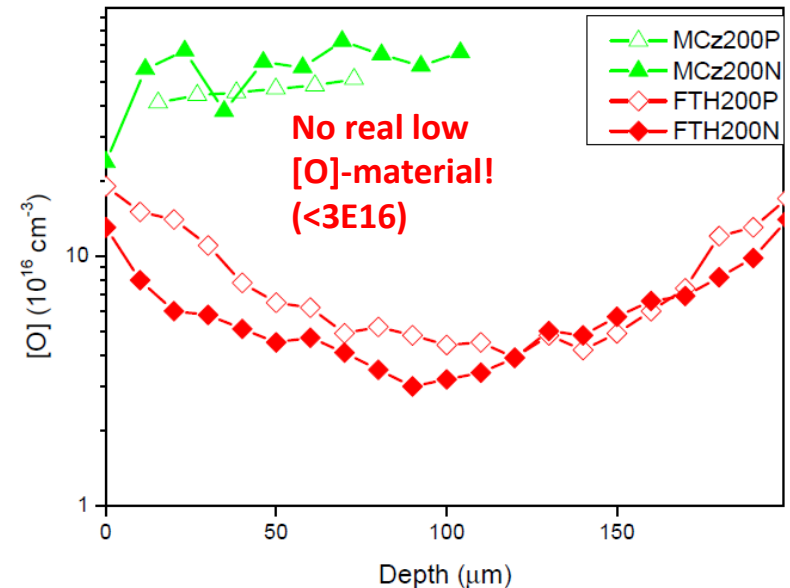
- **n-type**: p-on-n
- **p-type**: n-on-p
- Different oxygen concentr.
- Different thicknesses
- Different layouts (pad sensors, strip sensors, etc.)

production method	active thickness (physical thickness)	full-depletion Voltage		oxygen content
		n-type	p-type	
FZ -200	200 μm	90 V	120 V	$8 \cdot 10^{16} \text{ cm}^{-3}$
MCz -200	200 μm	150 V	100 V	$5 \cdot 10^{17} \text{ cm}^{-3}$
dd-FZ -200	$\sim 200 \mu\text{m}$ (320 μm)	100 V	90 V	$3 \cdot 10^{17} \text{ cm}^{-3}$
dd-FZ -300	$\sim 300 \mu\text{m}$ (320 μm)	190 V	230 V	$1 \cdot 10^{17} \text{ cm}^{-3}$

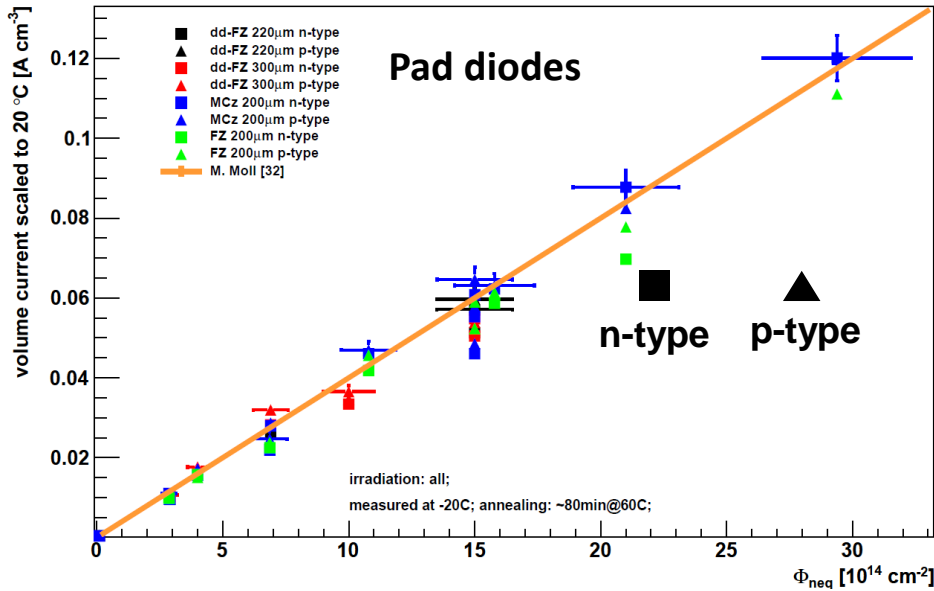
Irradiations performed

- 23 MeV protons (at Karlsruhe cyclotron, cooled),
 - **23 GeV protons** (at PS, CERN, up to 2weeks@RT),
 - **neutrons (~1 MeV)** (at JSI, Ljublj., up to 10min@RT)
- to particle fluences between $3 \cdot 10^{14} \text{ neq / cm}^2$ and $1.3 \cdot 10^{16} \text{ neq / cm}^2$

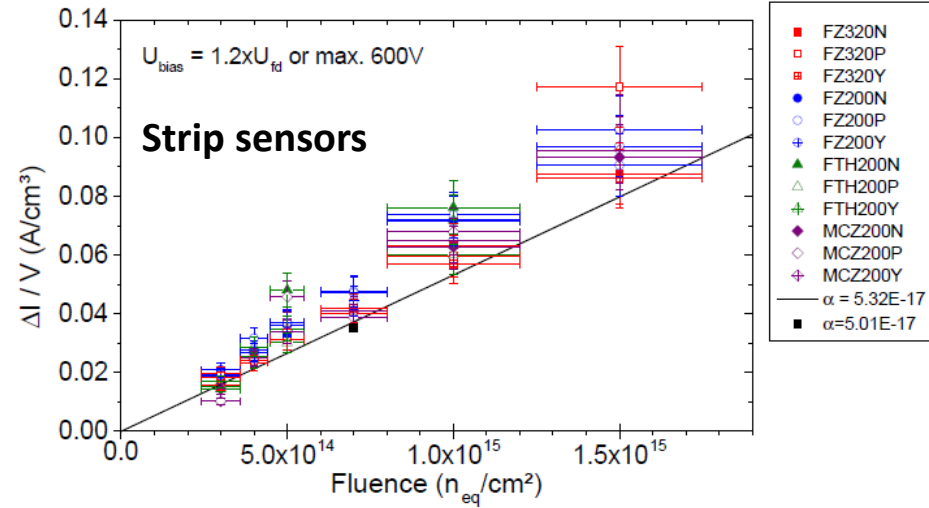
Strip detector: expect up to $\sim 2 \cdot 10^{15} \text{ neq/cm}^2$



Volume Current



Measured @V_dep+5%, -20°C, scaled to +20°C

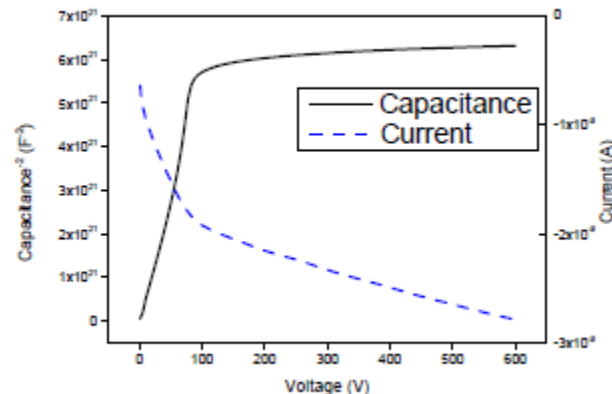
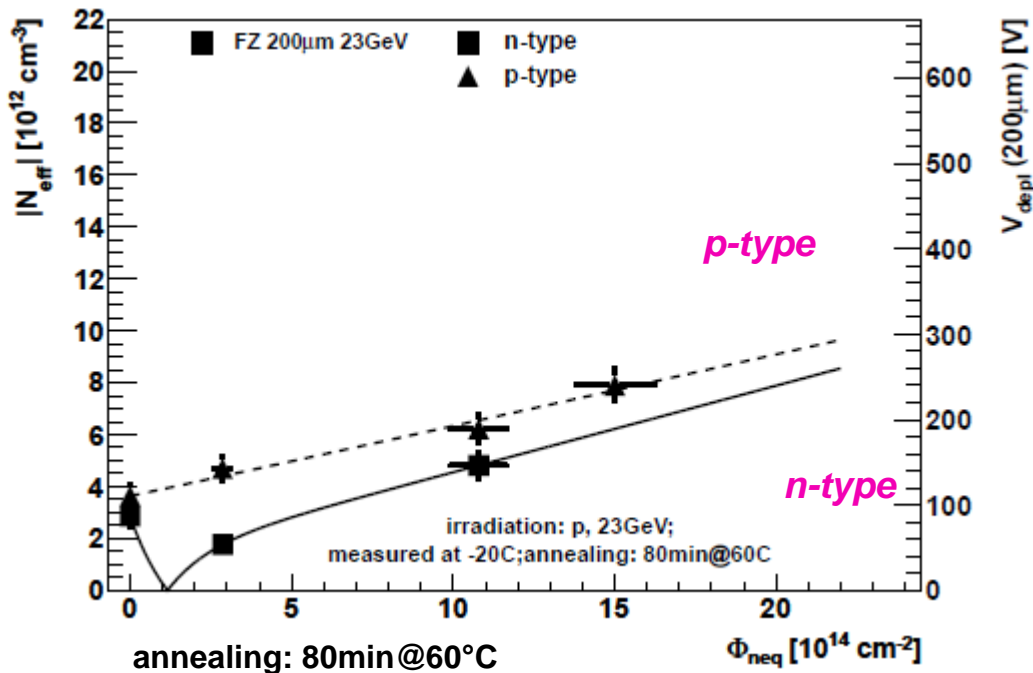


- Volume current scales with fluence:
- Scaling parameter independent of Si material, oxygen concentration
- Scaling parameter agrees with previous measurements M. Moll, PhD thesis, Hamburg 1999
- Note: Increased current seen in strip sensor

$$\frac{\Delta I}{V} = \alpha \Phi_{eq}$$

→ Current/ fluences understood
 → Independent of material
 → Independent of polarity
 → Cold operation necessary!

Depletion voltage: FZ Silicon after 23 GeV Proton and Neutron Irradiation



extracted from capacitance measurements
 @-20°C, 455 Hz
 (for comparison also @0°C, 1 kHz and 20°C,
 10 kHz for non-irradiated sensors)

V_{fd} determines the operation
 voltage needed

(RD50)

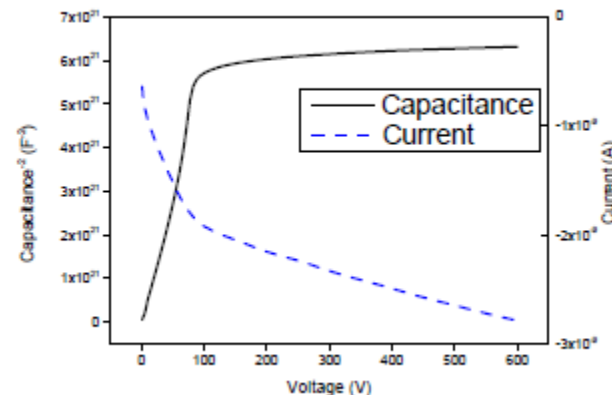
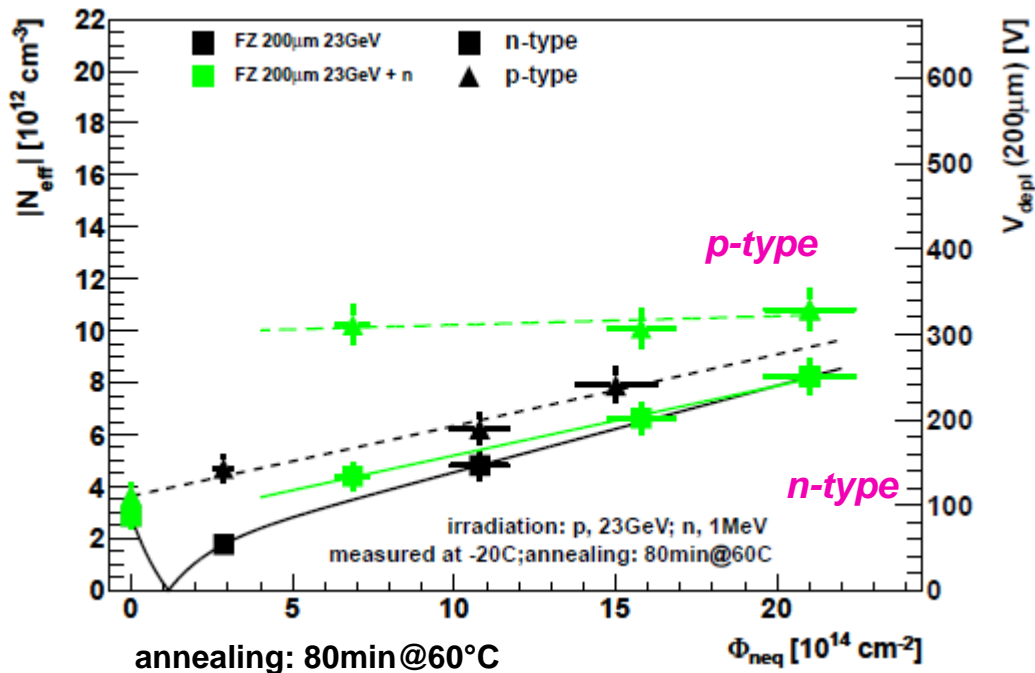
Note: Lower $r \rightarrow$ Higher $\Phi \rightarrow$ Higher p/n ratio

\Rightarrow Irradiation damage adds up, increase of V_{fd}

confirms \rightarrow

In low-oxygen material:
 neutrons \Rightarrow acceptors
 23 GeV protons \Rightarrow acceptors

Depletion voltage: FZ Silicon after 23 GeV Proton and Neutron Irradiation



extracted from capacitance measurements
 @-20°C, 455 Hz
 (for comparison also @0°C, 1 kHz and 20°C,
 10 kHz for non-irradiated sensors)

V_{fd} determines the operation
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(RD50)

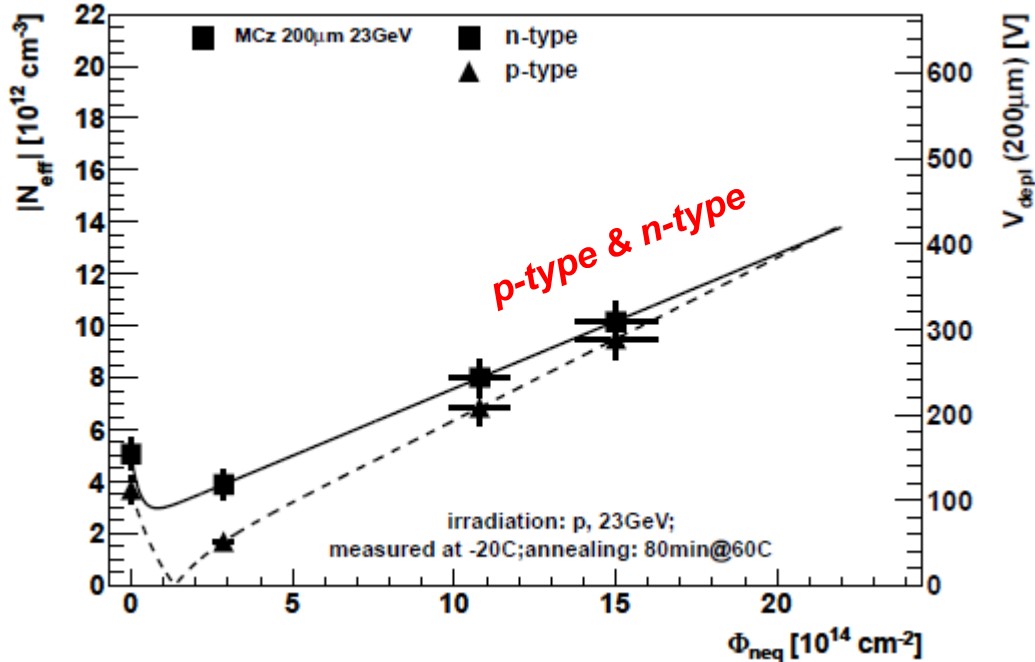
Note: Lower $r \rightarrow$ Higher $\Phi \rightarrow$ Higher p/n ratio

\Rightarrow Irradiation damage adds up, increase of V_{fd}

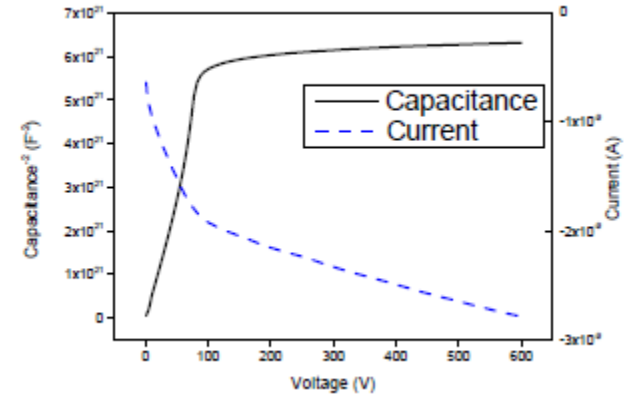
confirms \rightarrow

In low-oxygen material:
 neutrons \Rightarrow acceptors
 23 GeV protons \Rightarrow acceptors

Depletion voltage: MCz Silicon after 23 GeV Proton and Neutron Irradiation



extracted from capacitance measurements (-20°C, 455 Hz), annealing: 80min@60°C



extracted from capacitance measurements @-20°C, 455 Hz

(for comparison also @0°C, 1 kHz and 20°C, an 10 kHz for non-irradiated sensors)

V_{fd} determines the operation voltage needed

(RD50)

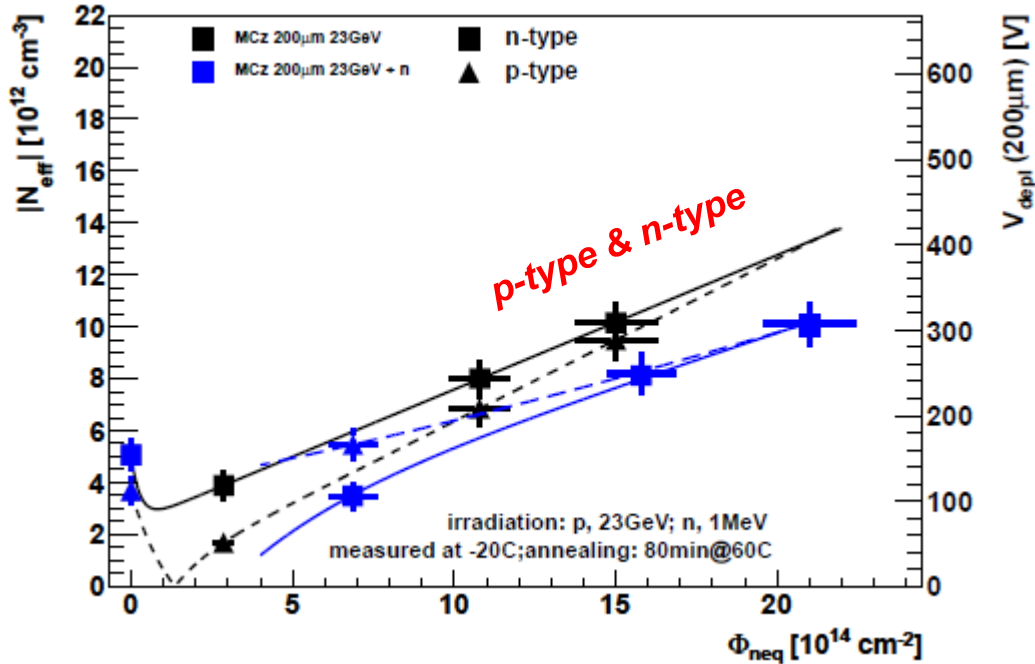
Note: Lower $r \rightarrow$ Higher $\Phi \rightarrow$ Higher p/n ratio

\Rightarrow Irradiation damage does not add up, no (strong) increase of V_{fd}

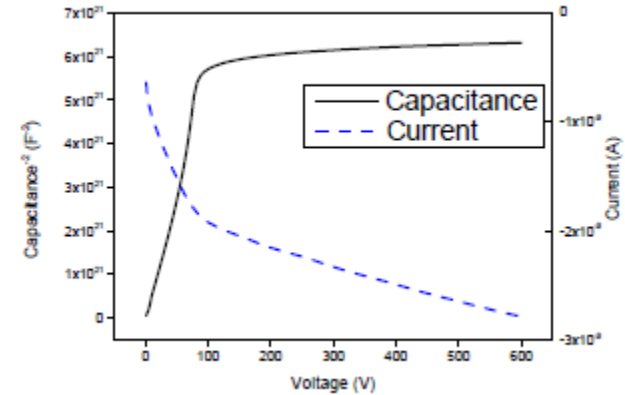
confirms \rightarrow

In high-oxygen material:
 neutrons \Rightarrow acceptors
 23 GeV protons \Rightarrow donors

Depletion voltage: MCz Silicon after 23 GeV Proton and Neutron Irradiation



extracted from capacitance measurements (-20°C, 455 Hz), annealing: 80min@60°C



extracted from capacitance measurements
 @-20°C, 455 Hz
 (for comparison also @0°C, 1 kHz and 20°C,
 an 10 kHz for non-irradiated sensors)

Note: Lower $r \rightarrow$ Higher $\Phi \rightarrow$ Higher p/n ratio

\Rightarrow Irradiation damage does not add up, no (strong) increase of V_{fd}

V_{fd} determines the operation voltage needed

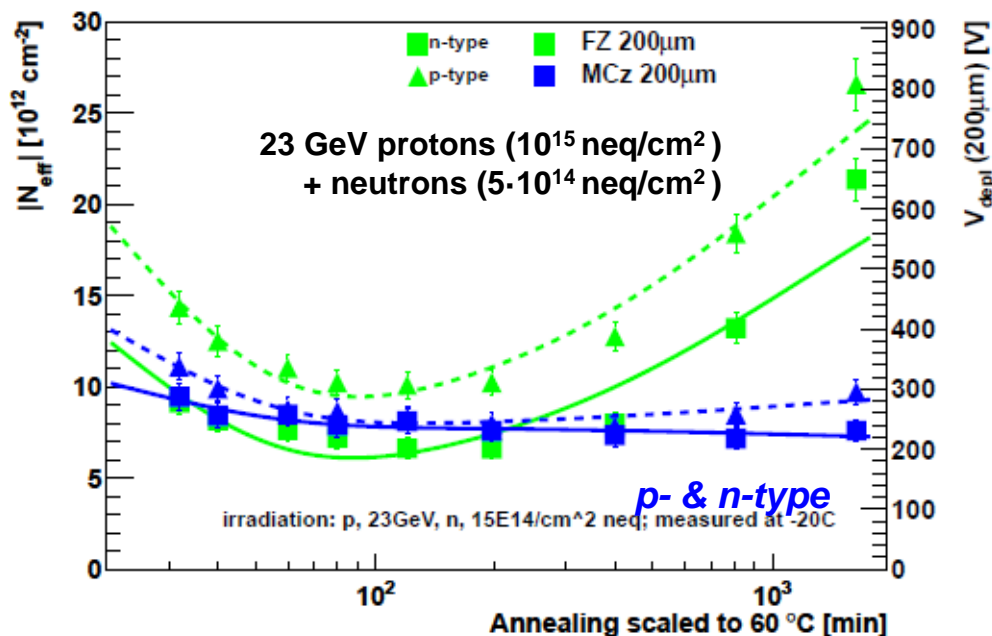
(RD50)

confirms \rightarrow

In high-oxygen material:
 neutrons \Rightarrow acceptors
 23 GeV protons \Rightarrow donors

Annealing of Full Depletion Voltage V_{fd} after Mixed Irradiation

V_{fd} after mixed irradiation



$V_{fd} < 600$ V for FZ and MCz (200 µm)

⇒ no signal loss at $V = 600$ V expected up to 400min@60°C (~7 weeks @ 20°C)

FZ: reverse annealing after

~100min@60°C (~12days @20°C)

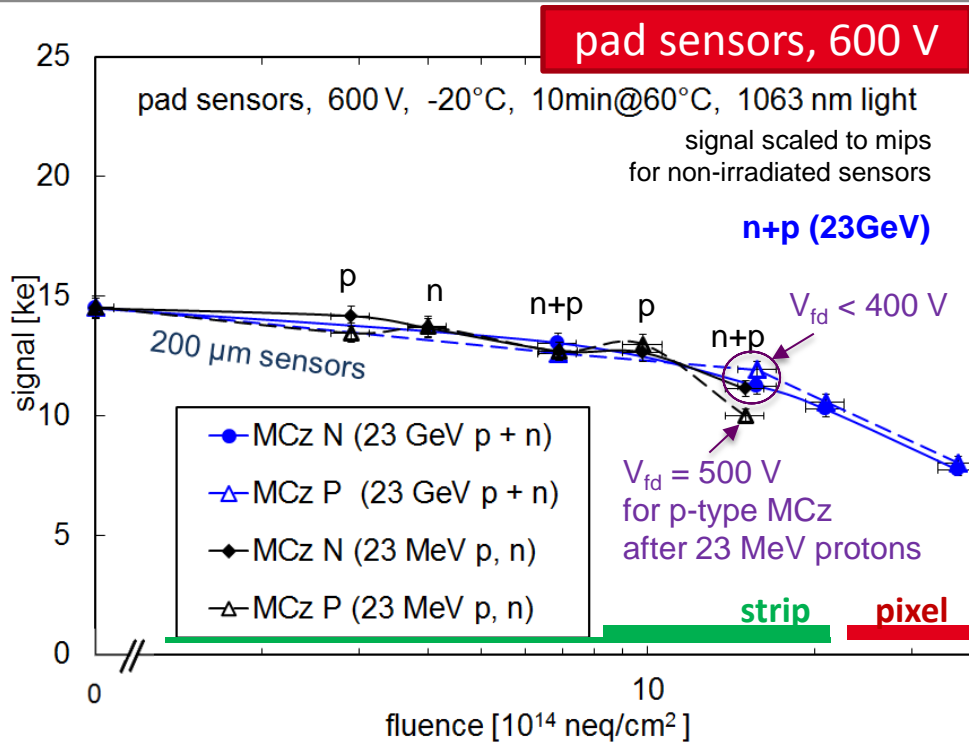
⇒ signal drop expected for high annealing times

MCz: beneficial annealing only

⇒ no signal drop expected

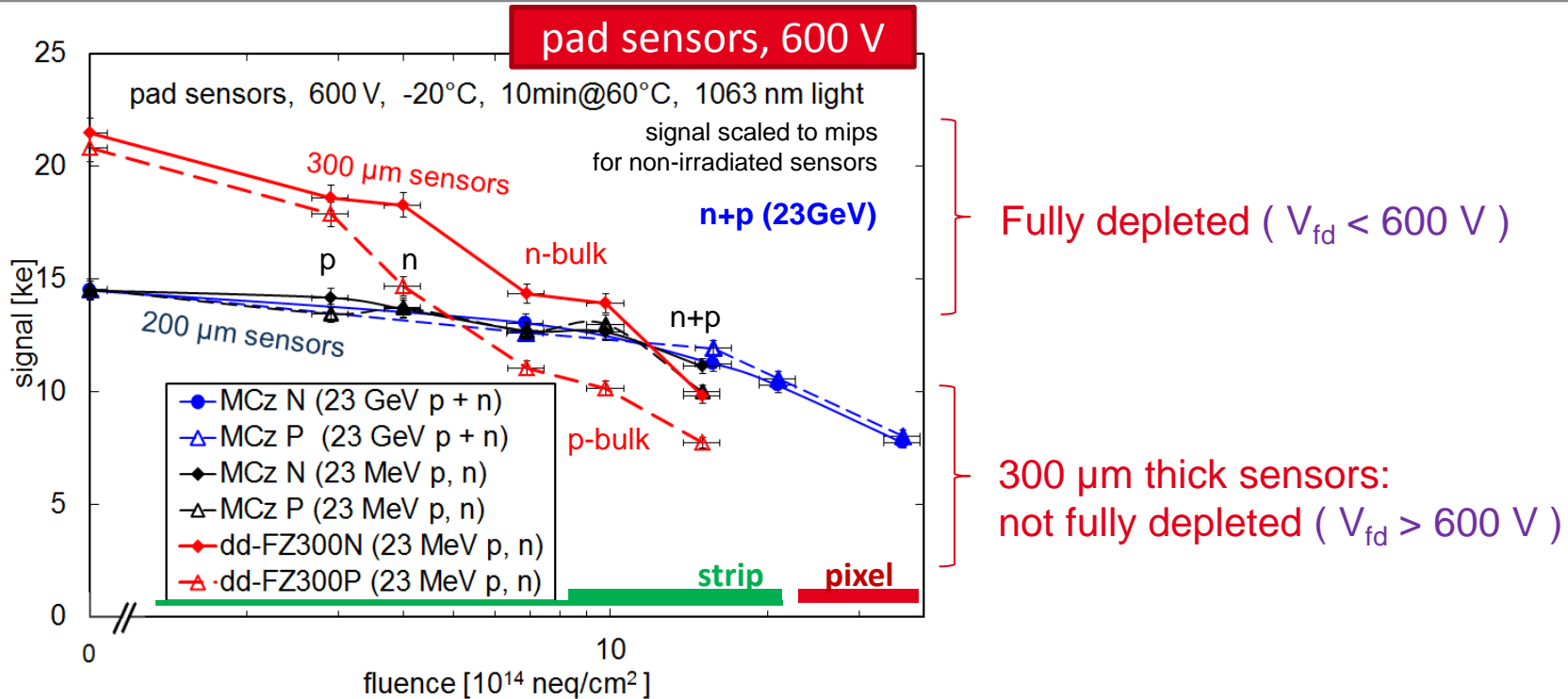
→ Comparison at minimum not full story.
 → Annealing needs to be taken into account, also high V_{dep} @ low t_{anneal}

Charge Collection in Pad Sensors after Different Irradiation Types



Signal independent of particle type (neutrons, 23 MeV protons, 23 GeV protons)
 and for pad sensors also of bulk doping (n-bulk vs. p-bulk) if $V \gg V_{fd}$

Charge Collection in Pad Sensors after Different Irradiation Types

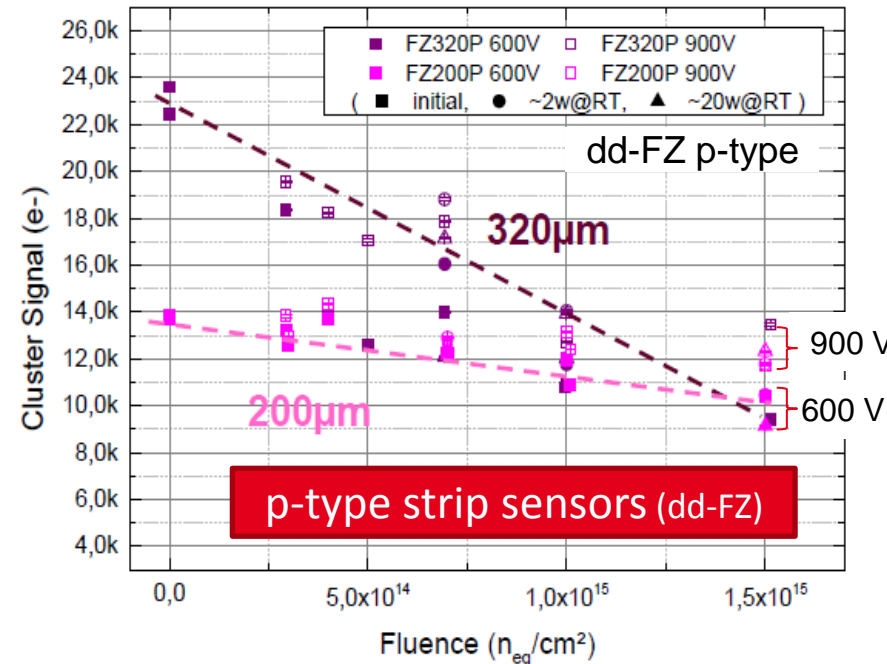
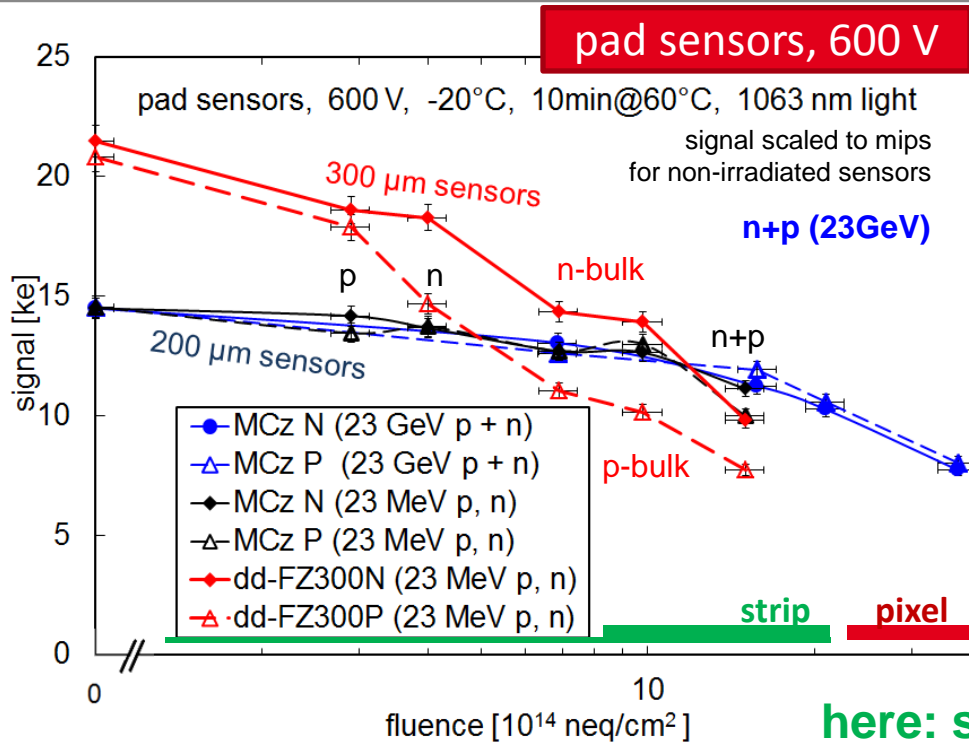


Signal independent of particle type (neutrons, 23 MeV protons, 23 GeV protons) and for pad sensors also of bulk doping (n-bulk vs. p-bulk) if $V \gg V_{fd}$

300 μm sensors **fully depleted** at low fluences \rightarrow **higher signals** than 200 μm sensors

300 μm sensors **not fully depleted** at high fluences \rightarrow **lower signals** than 200 μm sensors

Charge Collection in Pad and Strip Sensors after Different Irradiation Types



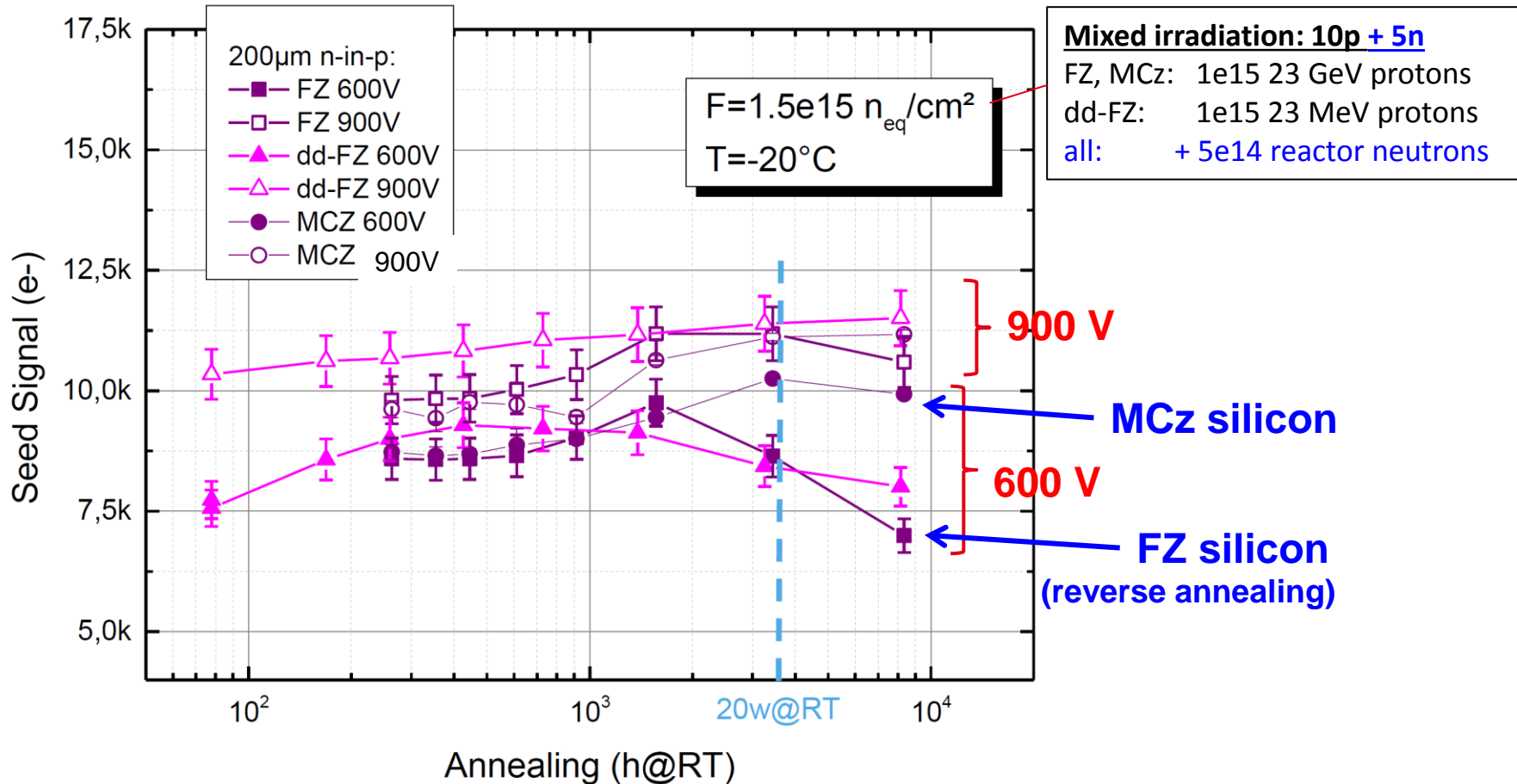
here: similar signals in p-type strip sensors

Signal independent of particle type (neutrons, 23 MeV protons, 23 GeV protons) and for pad sensors also of bulk doping (n-bulk vs. p-bulk) if $V \gg V_{fd}$

300 μm sensors **fully depleted** at low fluences → **higher signals** than 200 μm sensors

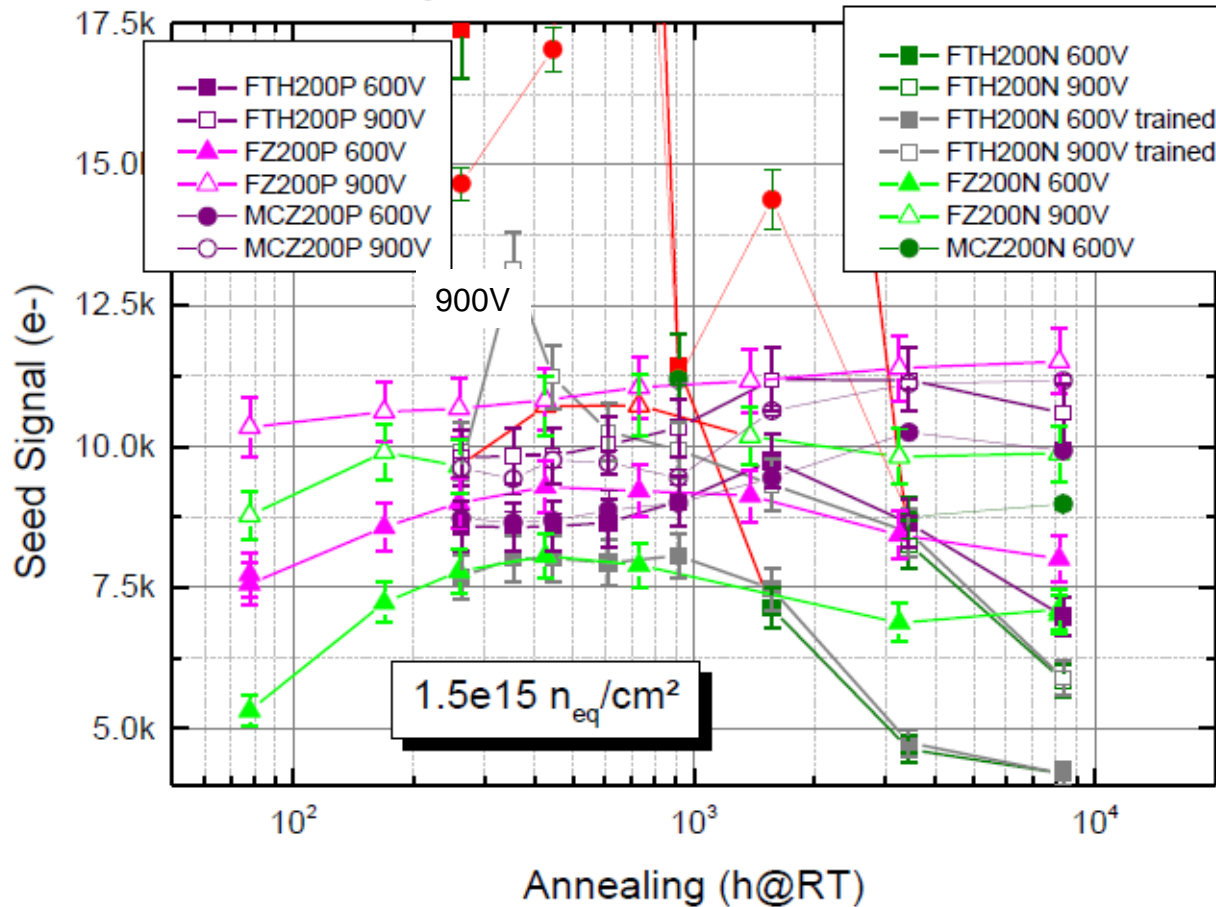
300 μm sensors **not fully depleted** at high fluences → **lower signals** than 200 μm sensors

200 μm Thick p-Type Strip Sensors: Seed Signal as a Function of Annealing Time



- **200 μm p-type sensors:** seed > 8 ke- at $1.5 \cdot 10^{15}$ neq/cm² up to ~20 weeks at RT
 ⇒ Can be operated in CMS strip tracker with 2 weeks annealing per year
- **MCz:** seed >8 ke- up to ~50 weeks at RT (long-term beneficial annealing)

Now with p versus n



Mixed irradiation: 10p + 5n
 FZ, MCz: 1e15 23 GeV protons
 dd-FZ: 1e15 23 MeV protons
 all: + 5e14 reactor neutrons

- n type sensors showed large noise, not all measurements reliable
- Tendency towards lower signal in n-type, drop at large annealing times

The R&D for the CMS outer tracker is well advanced

- Baseline tracker layout with barrel-endcap design
- Triggering at L1 → Trigger modules, 2S and PS → Module design
- CBC chip

CMS decided to use p-type silicon sensors for the phase II strip tracker.

- Seed signals $> 8 \text{ ke}$ @ $1.5\text{E}15$, stable with annealing for up to 20 weeks@RT (FZ) at RT and even 50 weeks (MCz)
- Noise under control (Our n-type sensors are affected by non-Gaussian noise: Talk by A. Nürnberg)
- Known advantage: Depletion from the front side, electron collection

Depletion voltage after mixed irradiation (23 GeV protons + neutrons)

- MCz silicon benefits from the compensation effect for mixed irradiation and from long-term beneficial annealing
- FZ silicon: no compensation and reverse annealing after >12 days at 20°C (90 min at 60°C)

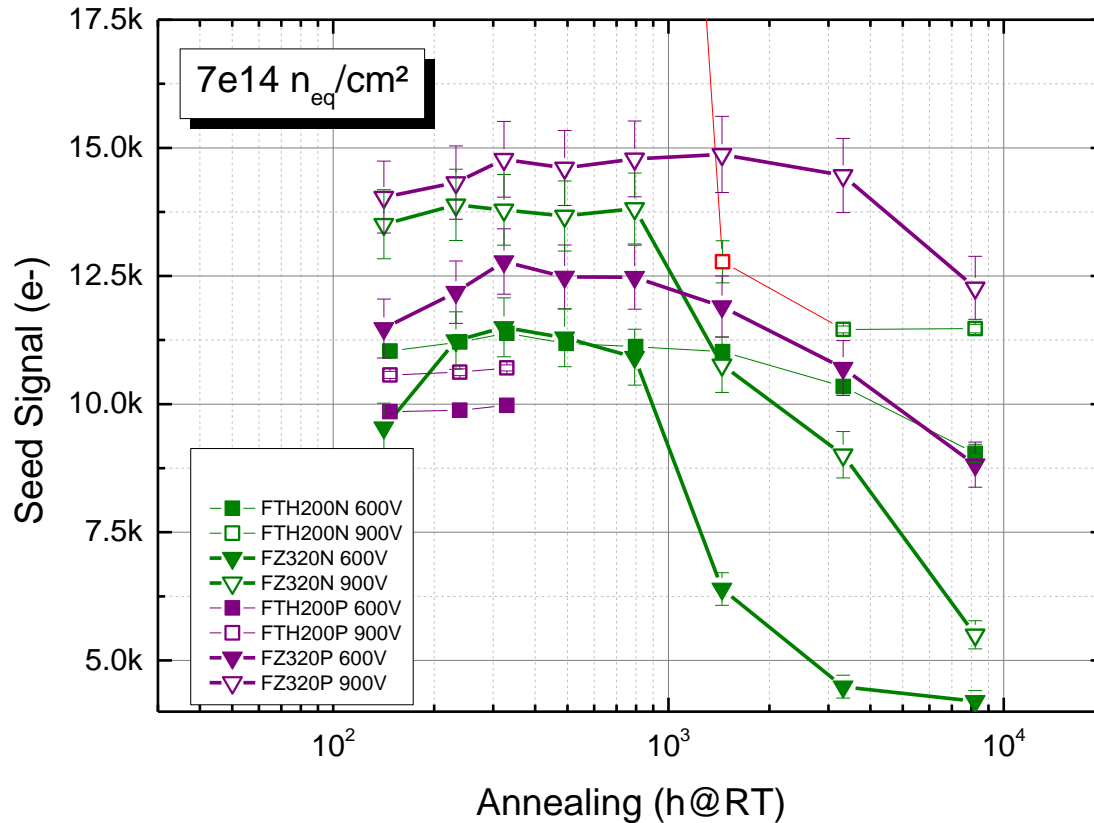
Further Remarks:

- Campaign did not include real low [O] FZ silicon → Smaller material dependence than “typical”
- Differences in V_{dep} after 23 GeV vs. 23 MeV proton irradiation, but similar signal if $V \gg V_{\text{fd}}$



Backup

Annealing – $7e14 n_{eq}/cm^2$ – FZ n and p

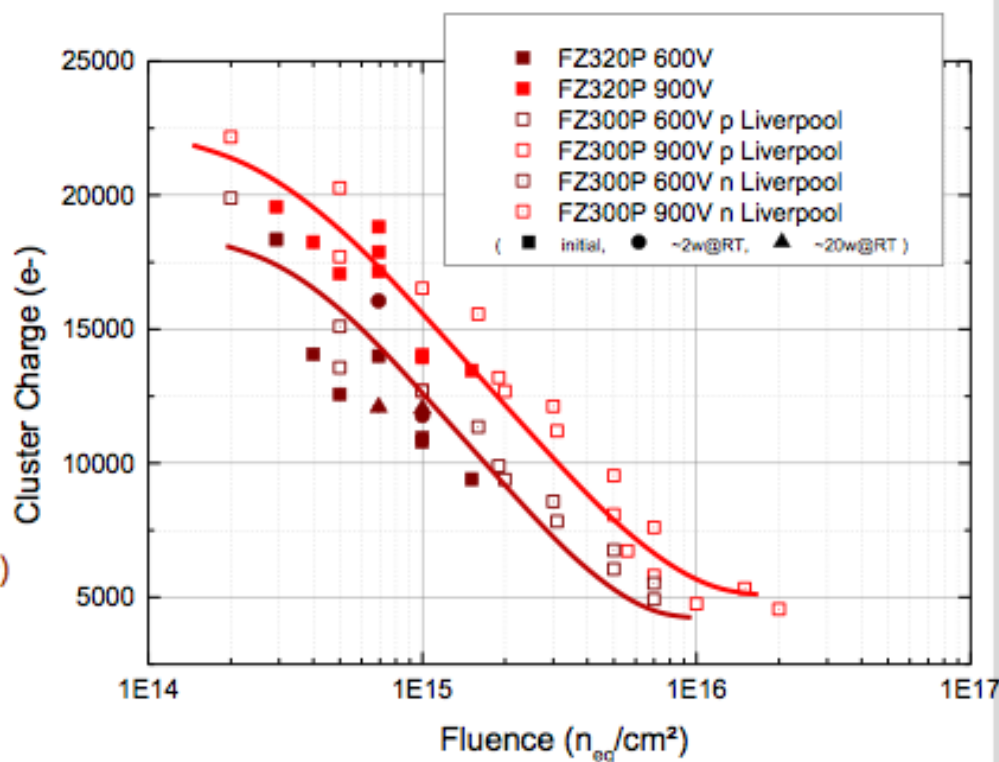


- n-type drops sharply after ~40days
- p-type very stable with annealing

Charge Collection – p-Type 300 μm Strip Sensors

- Charge collection measured with Sr90 at -20°C with 600V and 900V bias
- Liverpool (SCT128A) and Karlsruhe (Beetle) results show reasonable agreement
- p-type strip sensors show uniform drop like exponential decay,
 - e.g. for 600V in the range of $F=(1\text{e}14-1\text{e}16)n_{\text{eq}}/\text{cm}^2$:

$$CC \sim 5.7\text{ke}^- + 12.2\text{ke}^- \cdot \exp(-F/1.4\text{e}15 n_{\text{eq}}/\text{cm}^2)$$

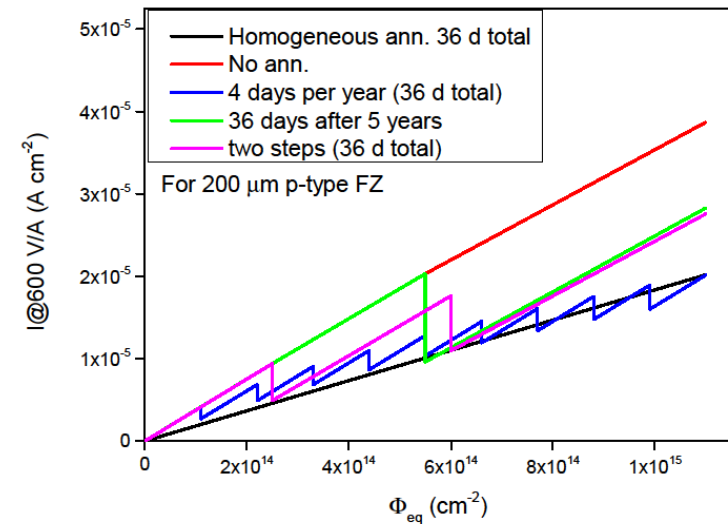
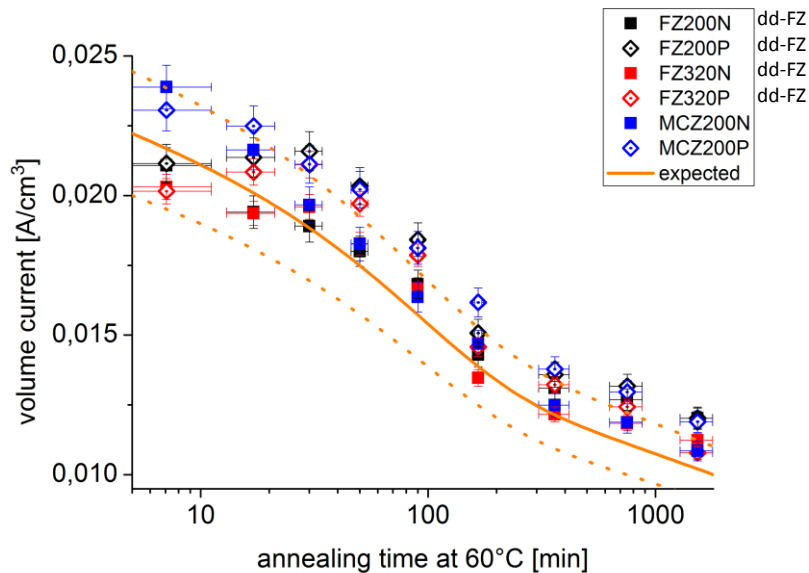


A. Dierlamm: Vertex 2013

Liverpool: NIM A 636 (2011) S56-S61

Annealing of Volume Current

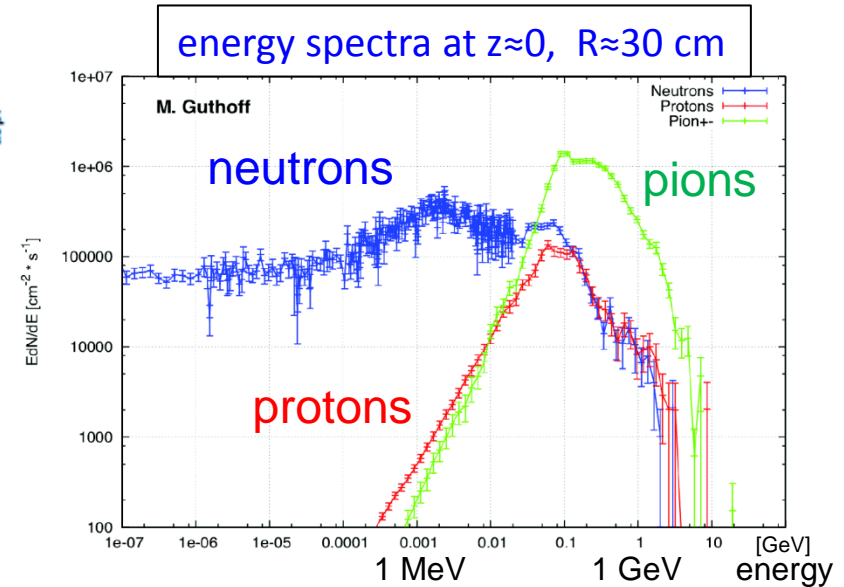
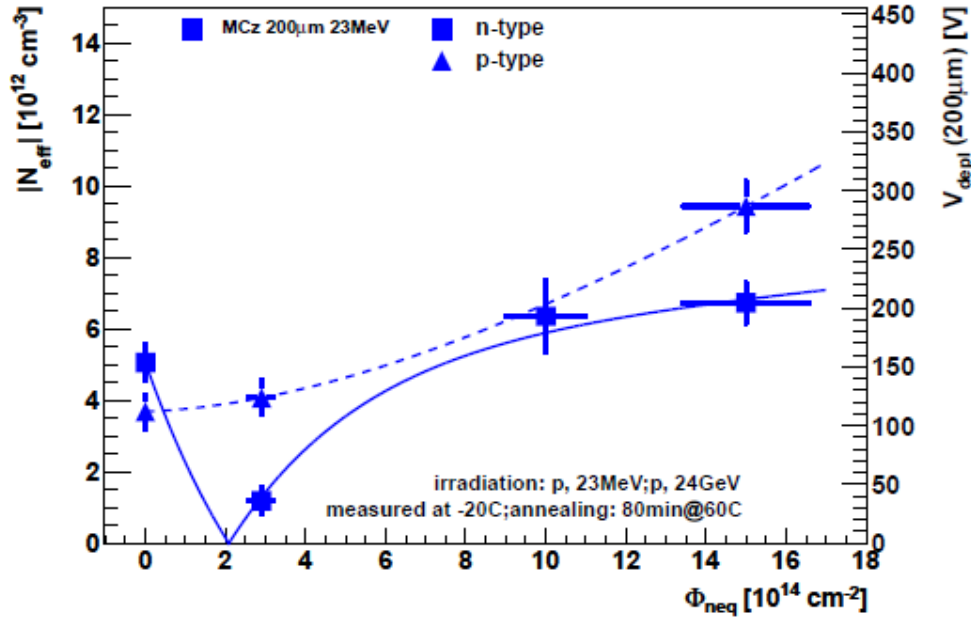
1 MeV neutrons, $\phi_{eq} = 4 \cdot 10^{14} \text{ cm}^{-2}$



- Current drop after annealing as expected
- Warmup can be beneficial, but need to also look at annealing of V_{dep}

Depletion voltage: Energy Dependence

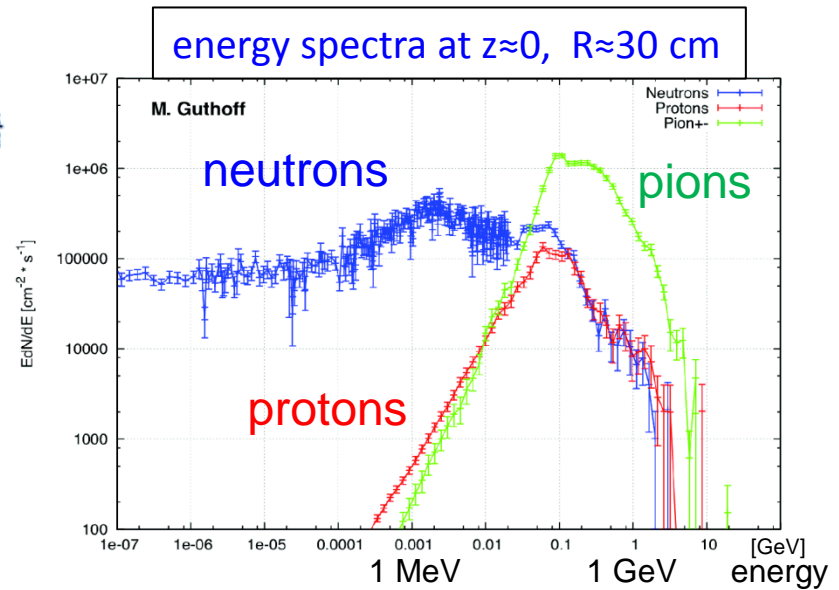
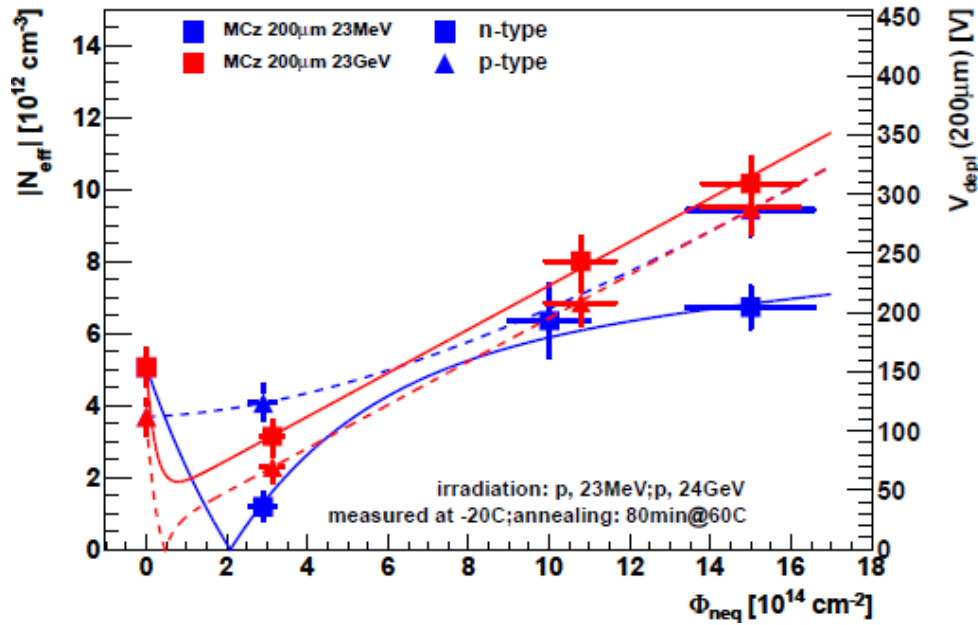
MCz Silicon after 23 GeV versus 23 MeV Proton Irradiation



Higher donor generation in 23 GeV protons \Rightarrow

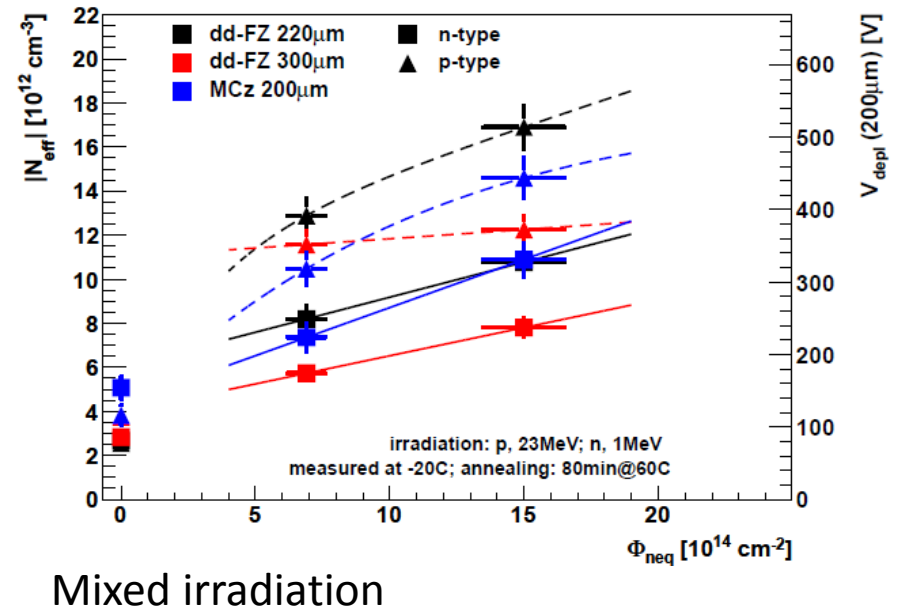
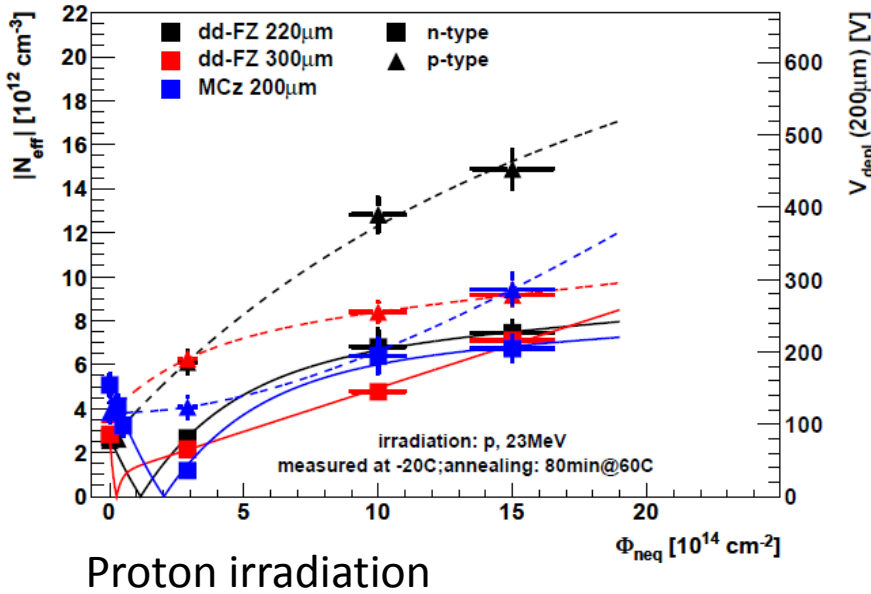
Depletion voltage: Energy Dependence

MCz Silicon after 23 GeV versus 23 MeV Proton Irradiation

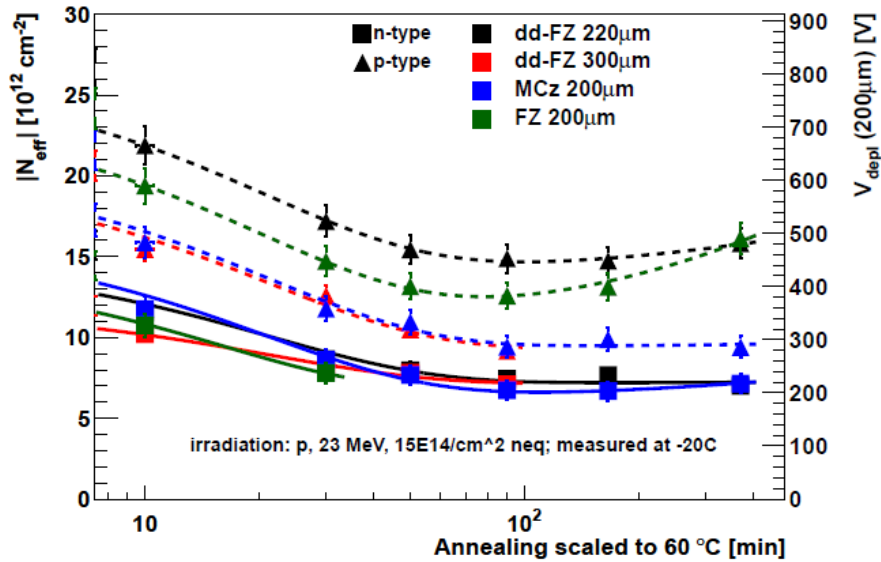


Higher donor generation in 23 GeV protons \Rightarrow

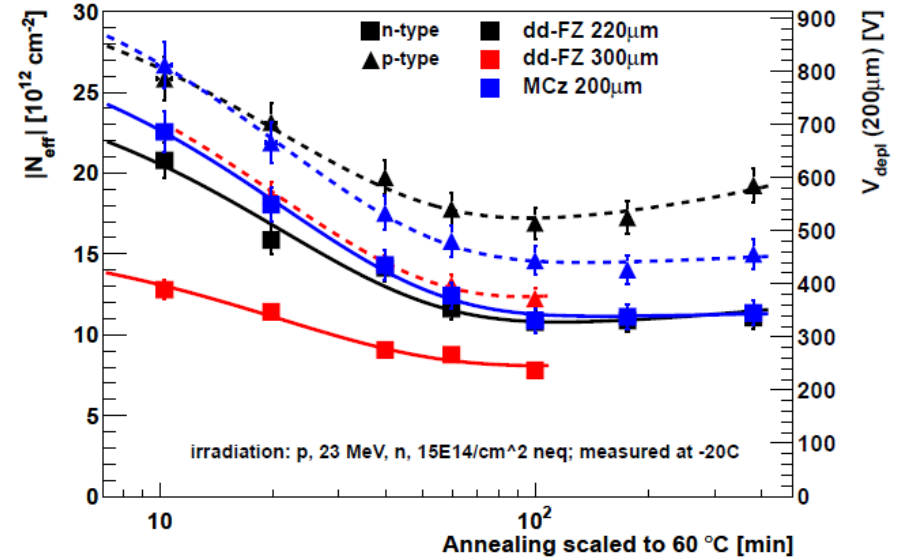
200 dd versus MCZ, MeV irradiation



200 dd versus MCZ, MeV irradiation

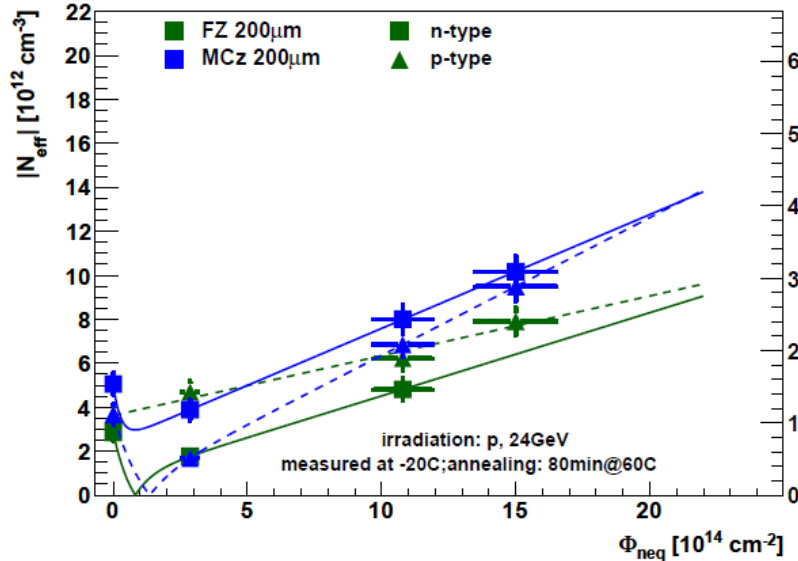


Proton irradiation

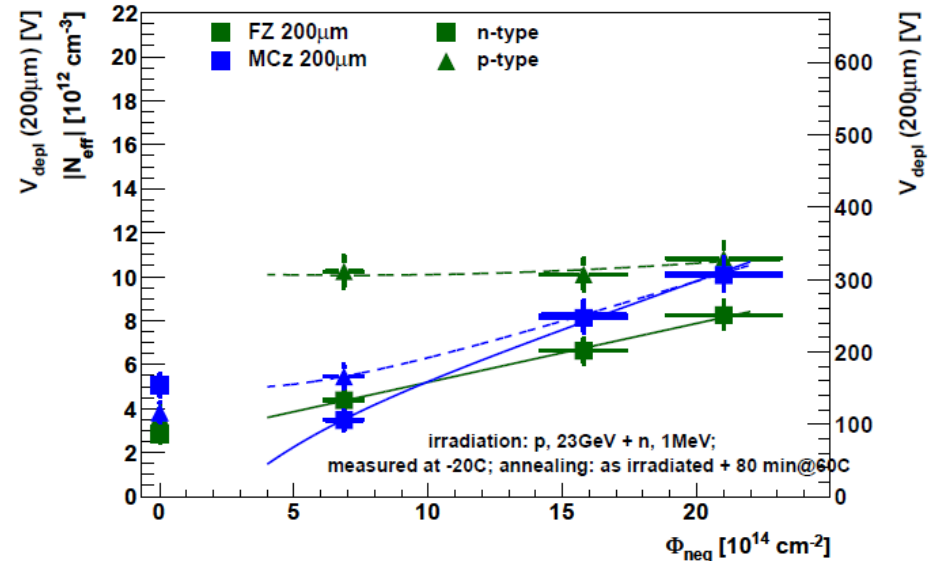


Mixed irradiation

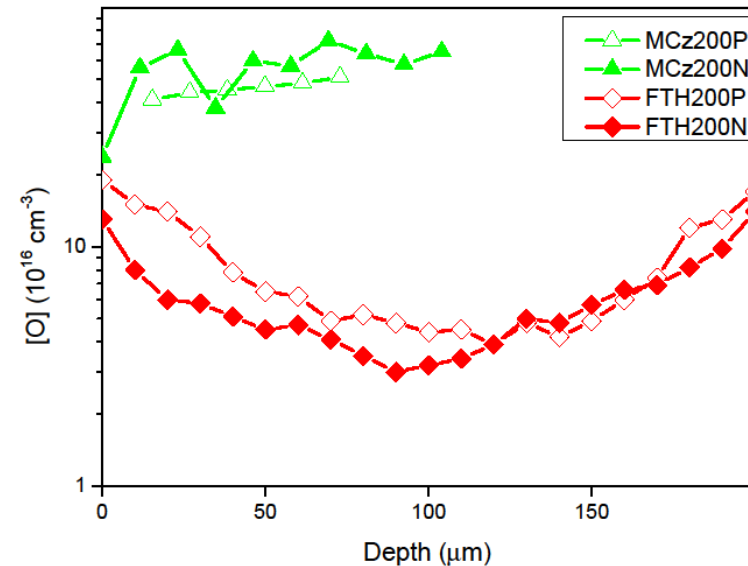
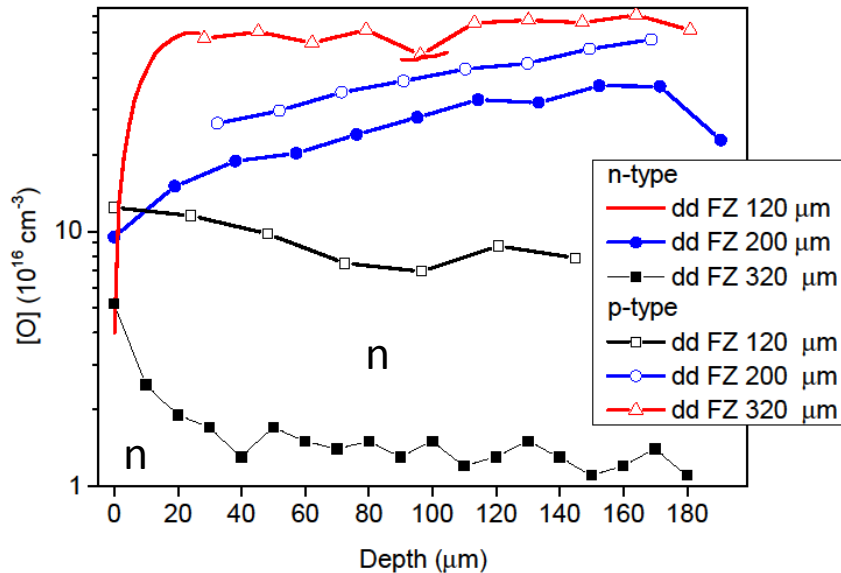
FZ 200 (FTH) versus MCZ, GeV irradiation



Proton irradiation



Mixed irradiation



- Deep diffused material: Higher [O] when active thickness lower
- [O] in p typically larger than n
- 120 dd extremely high!
- New: FTH and dd320n

- [O] FTH lower than MCZ but higher than typical FZ, more like DOFZ
- For reference: Standard FZ: $<3 \times 10^{16}$, DOFZ*: 1×10^{17}

New measurements:
FTH and dd-FZ 320 n

*Diffusion 72h at 1150°C